

FCC Test Report

(PART 27)

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Test Model: TA-1005

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Applicant: HMD Global Oy

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Issued By: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch

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(R.O.C)

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R.O.C

FCC Registration /

427177 / TW0011

Designation Number:





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Appendix – information on the Testing Laboratories				-		



Release Control Record

Issue No.	Description	Date Issued
RF170808C06-10	Original Release	Nov. 16, 2017



1 Certificate of Conformity

Product: Smart Phone

Brand: Nokia

Test Model: TA-1005

Sample Status: Identical Prototype

Applicant: HMD Global Oy

Test Date: Aug. 19, 2017 ~ Oct. 25, 2017

Standards: FCC Part 27, Subpart C, L

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Ivonne Wu / Supervisor

Dylan Chiou / Project Engineer



2 Summary of Test Results

	Applied Standard: FCC Part 27 & Part 2 (WCDMA)				
FCC Clause	Test Item	Result	Remarks		
2.1046 27.50(d)(4)	Equivalent Isotropic Radiated Power	Pass	Meet the requirement of limit.		
2.1055 27.54	Frequency Stability	Pass	Meet the requirement of limit.		
2.1049 27.53(h)	Occupied Bandwidth	Pass	Meet the requirement of limit.		
27.50(d)(5)	Peak to Average Ratio	Pass	Meet the requirement of limit.		
27.53(h)	Band Edge Measurements	Pass	Meet the requirement of limit.		
2.1051 27.53(h)	Conducted Spurious Emissions	Pass	Meet the requirement of limit.		
2.1053 27.53(h)	Radiated Spurious Emissions	Pass	Meet the requirement of limit. Minimum passing margin is -35.41 dB at 3465.20 MHz.		

	Applied Standard: FCC Part 27 & Part 2 (LTE 4)					
FCC Clause	Test Item	Result	Remarks			
2.1046 27.50(d)(4)	Maximum Peak Output Power	Pass	Meet the requirement of limit.			
2.1055 27.54	Frequency Stability	Pass	Meet the requirement of limit.			
2.1049 27.53(h)	Occupied Bandwidth	Pass	Meet the requirement of limit.			
27.50(d)(5)	Peak to Average Ratio	Pass	Meet the requirement of limit.			
27.53(h)	Band Edge Measurements	Pass	Meet the requirement of limit.			
2.1051 27.53(h)	Conducted Spurious Emissions	Pass	Meet the requirement of limit.			
2.1053 27.53(h)	Radiated Spurious Emissions	Pass	Meet the requirement of limit. Minimum passing margin is -31.74 dB at 5197.50 MHz.			



	Applied Standard: FCC Part 27 & Part 2 (LTE 12)					
FCC Clause	Test Item	Result	Remarks			
2.1046 27.50(C)(10)	Maximum Peak Output Power	Pass	Meet the requirement of limit.			
2.1055 27.54	Frequency Stability	Pass	Meet the requirement of limit.			
2.1049 27.53(g)	Occupied Bandwidth	Pass	Meet the requirement of limit.			
27.50(d)(5)	Peak to Average Ratio	Pass	Meet the requirement of limit.			
27.53(g)	Band Edge Measurements	Pass	Meet the requirement of limit.			
2.1051 27.53(g)	Conducted Spurious Emissions	Pass	Meet the requirement of limit.			
2.1053 27.53(g)	Radiated Spurious Emissions	Pass	Meet the requirement of limit. Minimum passing margin is -43.48 dB at 1408.00 MHz.			

	Applied Standard: FCC Part 27 & Part 2 (LTE 13)					
FCC Clause	Test Item	Result	Remarks			
2.1046 27.50(b)(10)	Maximum Peak Output Power	Pass	Meet the requirement of limit.			
2.1055 27.54	Frequency Stability	Pass	Meet the requirement of limit.			
2.1049 27.53(g)	Occupied Bandwidth	Pass	Meet the requirement of limit.			
27.50(d)(5)	Peak to Average Ratio	Pass	Meet the requirement of limit.			
27.53(g)	Band Edge Measurements	Pass	Meet the requirement of limit.			
2.1051 27.53(g)	Conducted Spurious Emissions	Pass	Meet the requirement of limit.			
2.1053 27.53(g)(f)	Radiated Spurious Emissions	Pass	Meet the requirement of limit. Minimum passing margin is -18.50 dB at 1564.00 MHz.			



	Applied Standard: FCC Part 27 & Part 2 (LTE 17)					
FCC Clause	Test Item	Result	Remarks			
2.1046 27.50(C)(10)	Maximum Peak Output Power	Pass	Meet the requirement of limit.			
2.1055 27.54	Frequency Stability	Pass	Meet the requirement of limit.			
2.1049 27.53(g)	Occupied Bandwidth	Pass	Meet the requirement of limit.			
27.50(d)(5)	Peak to Average Ratio	Pass	Meet the requirement of limit.			
27.53(g)	Band Edge Measurements	Pass	Meet the requirement of limit.			
2.1051 27.53(g)	Conducted Spurious Emissions	Pass	Meet the requirement of limit.			
2.1053 27.53(g)	Radiated Spurious Emissions	Pass	Meet the requirement of limit. Minimum passing margin is -41.69 dB at 249.78 MHz.			

2.1 Measurement Uncertainty

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2:

Measurement	Frequency	Expended Uncertainty (k=2) (±)
Conducted Emissions at mains ports	150 kHz ~ 30 MHz	2.44 dB
Padiated Emissions up to 1 CHz	30 MHz ~ 200 MHz	2.0153 dB
Radiated Emissions up to 1 GHz	200 MHz ~ 1000 MHz	2.0224 dB
Radiated Emissions above 1 GHz	1 GHz ~ 18 GHz	1.0121 dB
Radiated Effissions above 1 GHz	18 GHz ~ 40 GHz	1.1508 dB



2.2 Test Site and Instruments

Description & Manaufacturer	Model No.	Serial No.	Date of Calibration	Due Date of Calibration
Test Receiver Agilent Technologies	N9038A	MY52260177	Jul. 05, 2017	Jul. 04, 2018
Spectrum Analyzer ROHDE & SCHWARZ	FSU43	101261	Dec. 13, 2016	Dec. 12, 2017
BILOG Antenna SCHWARZBECK	VULB9168	9168-472	Dec. 13, 2016	Dec. 12, 2017
HORN Antenna ETS-Lindgren	3117	00143293	Jun. 26, 2017	Jun. 25, 2018
Double Ridge Guide Horn Antenna EMCO	3115	5619	Dec. 15, 2016	Dec. 14, 2017
BILOG Antenna SCHWARZBECK	VULB 9168	9168-153	Dec. 13, 2016	Dec. 12, 2017
HORN Antenna SCHWARZBECK	BBHA 9170	9170-480	Dec. 14, 2016	Dec. 13, 2017
Fixed Attenuator Mini-Circuits	BW-N10W5+	NA	Jul. 07, 2017	Jul. 06, 2018
MXG Vector signal generator Agilent	N5182B	MY53050430	Oct. 19, 2016	Oct. 18, 2017
MXG Vector signal generator Agilent	N5182B	MY53050430	Oct. 24, 2017	Oct. 23, 2018
Preamplifier Agilent	310N	187226	Jun. 23, 2017	Jun. 22, 2018
Preamplifier Agilent	83017A	MY39501357	Jun. 23, 2017	Jun. 22, 2018
Power Meter Anritsu	ML2495A	1012010	Aug. 15, 2017	Aug. 14, 2018
Power Sensor Anritsu	MA2411B	1315050	Aug. 15, 2017	Aug. 14, 2018
RF signal cable ETS-LINDGREN	5D-FB	Cable-CH1-01(R FC-SMS-100-SM S-120+RFC-SMS -100-SMS-400)	Jun. 26, 2017	Jun. 25, 2018
RF signal cable ETS-LINDGREN	8D-FB	Cable-CH1-02(R FC-SMS-100-SM S-24)	Jun. 26, 2017	Jun. 25, 2018
Software BV ADT	E3 8.130425b	NA	NA	NA
Antenna Tower MF	NA	NA	NA	NA
Turn Table MF	NA	NA	NA	NA
Antenna Tower &Turn Table Controller MF	MF-7802	NA	NA	NA
Communications Tester-Wireless Agilent	8960 Series 10	MY53201073	Jun. 28, 2017	Jun. 27, 2019
Radio Communication Analyzer Anritsu	MT8820C	6201010284	Nov. 30, 2016	Nov. 29, 2017



Note:	2. 3.	The calibration interval of the above test instruments is 12 / 24 months and the calibrations are traceable to NML/ROC and NIST/USA. The test was performed in HsinTien Chamber 1. The horn antenna and preamplifier (model: 83017A) are used only for the measurement of emission frequency above 1 GHz if tested. The IC Site Registration No. is IC7450I-1.



3 General Information

3.1 General Description of EUT

Product	Smart Phone			
Brand	Nokia			
Test Model	TA-1005			
Status of EUT	Identical Prototype			
Power Supply Rating	5 Vdc or 9 Vdc or 12 Vdc (adapter) 5 Vdc (host equipment) 3.85 Vdc (battery)			
Madaladan Torra	WCDMA	QPSK		
Modulation Type	LTE	QPSK, 16QAM, 64QAM		
	WCDMA	1712.4 ~ 1752.6 MHz		
	LTE Band 4 (Channel Bandwidth: 1.4 MHz)	1710.7 ~ 1754.3 MHz		
	LTE Band 4 (Channel Bandwidth: 3 MHz)	1711.5 ~ 1753.5 MHz		
	LTE Band 4 (Channel Bandwidth: 5 MHz)	1712.5 ~ 1752.5 MHz		
	LTE Band 4 (Channel Bandwidth: 10 MHz)	1715.0 ~ 1750.0 MHz		
	LTE Band 4 (Channel Bandwidth: 15 MHz)	1717.5 ~ 1747.5 MHz		
	LTE Band 4 (Channel Bandwidth: 20 MHz)	1720.0 ~ 1745.0 MHz		
Frequency Range	LTE Band 12 (Channel Bandwidth: 1.4 MHz)	699.7 ~ 715.3 MHz		
	LTE Band 12 (Channel Bandwidth: 3 MHz)	700.5 ~ 714.5 MHz		
	LTE Band 12 (Channel Bandwidth: 5 MHz)	701.5 ~ 713.5 MHz		
	LTE Band 12 (Channel Bandwidth: 10 MHz) 704.0 ~ 711.0 MHz			
	LTE Band 13 (Channel Bandwidth: 5 MHz)	779.5 ~ 784.5 MHz		
	LTE Band 13 (Channel Bandwidth: 10 MHz)	782.0 MHz		
	LTE Band 17 (Channel Bandwidth: 5 MHz)	706.5 ~ 713.5 MHz		
	LTE Band 17 (Channel Bandwidth: 10 MHz)	709.0 ~ 711.0 MHz		
	WCDMA	4M14F9W		
	LTE Band 4 (Channel Bandwidth: 1.4 MHz)	1M09G7D		
	LTE Band 4 (Channel Bandwidth: 3 MHz)	2M70G7D		
	LTE Band 4 (Channel Bandwidth: 5 MHz)	4M50W7D		
	LTE Band 4 (Channel Bandwidth: 10 MHz)	8M98W7D		
	LTE Band 4 (Channel Bandwidth: 15 MHz)	13M5G7D		
	LTE Band 4 (Channel Bandwidth: 20 MHz)	18M0W7D		
Emission Designator	LTE Band 12 (Channel Bandwidth: 1.4 MHz)	1M09W7D		
	LTE Band 12 (Channel Bandwidth: 3 MHz)	2M70G7D		
	LTE Band 12 (Channel Bandwidth: 5 MHz)	4M49W7D		
	LTE Band 12 (Channel Bandwidth: 10 MHz)	8M97W7D		
	LTE Band 13 (Channel Bandwidth: 5 MHz)	4M49W7D		
	LTE Band 13 (Channel Bandwidth: 10 MHz)	8M95G7D		
	LTE Band 17 (Channel Bandwidth: 5 MHz)	4M49W7D		
	LTE Band 17 (Channel Bandwidth: 10 MHz)	8M97W7D		



	LTE Band 12 (Channel Bandwidth: 1.4 MHz)	56.51 mW		
	LTE Band 12 (Channel Bandwidth: 3 MHz)	56.87 mW		
	LTE Band 12 (Channel Bandwidth: 5 MHz)	56.96 mW		
Max. ERP Power	LTE Band 12 (Channel Bandwidth: 10 MHz)	57.66 mW		
Wax. ERP Power	LTE Band 13 (Channel Bandwidth: 5 MHz)	56.94 mW		
	LTE Band 13 (Channel Bandwidth: 10 MHz)	57.37 mW		
	LTE Band 17 (Channel Bandwidth: 5 MHz)	202.72 mW		
	LTE Band 17 (Channel Bandwidth: 10 MHz)	206.49 mW		
	WCDMA	161.70 mW		
	LTE Band 4 (Channel Bandwidth: 1.4 MHz)	160.88 mW		
	LTE Band 4 (Channel Bandwidth: 3 MHz)	162.07 mW		
Max. EIRP Power	LTE Band 4 (Channel Bandwidth: 5 MHz)	160.21 mW		
	LTE Band 4 (Channel Bandwidth: 10 MHz)	160.69 mW		
	LTE Band 4 (Channel Bandwidth: 15 MHz)	160.95 mW		
	LTE Band 4 (Channel Bandwidth: 20 MHz)	165.84 mW		
Antenna Type	Fixed Internal Antenna			
Accessory Device	Refer to Note as below			
Data Cable Supplied	Refer to Note as below			

Note:

1. The EUT contains following accessory devices.

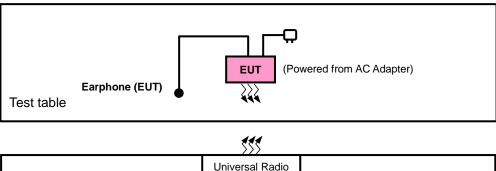
Product	Brand	Model	Description
Adapter	Salcomp	FC0302	I/P: 100-240 Vac, 0.5 A O/P: 5 Vdc, 2.5 A or 9 Vdc, 2 A or 12 Vdc, 1.5 A
Battery	SCUD	HE333	3.85 Vdc, 3250 mAh
Earphone	NOKIA	HS-A01	1.15 meter
USB Cable	Foxconn	CUDT01E-FA210-EH	0.95 meter
LCD Panel	LG Display	LH546QH1-EDD1-QG1	5.5" OLED
Front Camera	Chicony	CBFH51020005020LH	5M
Main Camera	Primay	FCDC1N	12+13M
eMMC 1 (=ROM 1)	SAMSUNG	IC_UFS2.1_128G	128G
Main Board	AT&S	FIH1883	
BT/WLAN Module	murata	LBDD5QA1MS-119	
WWAN Module	Qualcomm	MSM8998	

2. The above EUT information is declared by manufacturer and for more detailed features description, please refer to the manufacturer's specifications or user's manual.



3.2 Configuration of System under Test

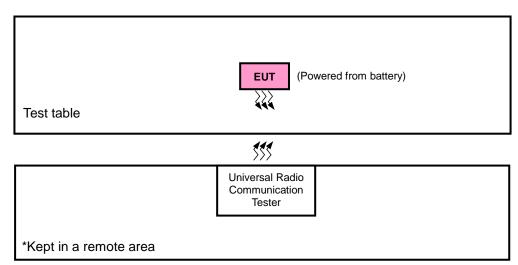
<Radiated Emission Test>



Universal Radio
Communication
Tester

*Kept in a remote area

<E.R.P. / E.I.R.P. Test>



3.2.1 Description of Support Units

The EUT has been tested as an independent unit together with other necessary accessories or support units.



3.3 Test Mode Applicability and Tested Channel Detail

Pre-Scan has been conducted to determine the worst-case mode from all possible combinations between available modulations, data rates, XYZ axis, and antenna ports

The worst case was found when positioned as the table below. Following channel(s) was (were) selected for the final test as listed below:

Antenna	Band	ERP / EIRP	Radiated Emission
0	WCDMA	X-plane	Y-axis
U	LTE Band 4	X-plane	X-axis
	LTE Band 12	X-plane	X-axis
1	LTE Band 13	X-plane	X-axis
	LTE Band 17	X-plane	X-axis

Note: The EUT incorporates WWAN diversity antenna.

WCDMA

EUT Configure Mode	Test Item Available Channel		Tested Channel	Mode
-	EIRP	1312 to 1513	1312, 1413, 1513	WCDMA
-	Frequency Stability	1312 to 1513	1312, 1513	WCDMA
-	Occupied Bandwidth	1312 to 1513	1312, 1413, 1513	WCDMA
-	Band Edge	1312 to 1513	1312, 1513	WCDMA
-	Peak to Average Ratio	1312 to 1513	1312, 1413, 1513	WCDMA
-	Condcudeted Emission	1312 to 1513	1312, 1413, 1513	WCDMA
-	Radiated Emission	1312 to 1513	1312, 1413, 1513	WCDMA



LTE Band 4

EUT Configure Mode	Test Item	Available Channel	Tested Channel	Channel Bandwidth	Modulation	Mode
		19957 to 20393	19957, 20175, 20393	1.4 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		19965 to 20385	19965, 20175, 20385	3 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
_	EIRP	19975 to 20375	19975, 20175, 20375	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
	LIKI	20000 to 20350	20000, 20175, 20350	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		20025 to 20325	20025, 20175, 20325	15 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		20050 to 20300	20050, 20175, 20300	20 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		19957 to 20393	19957, 20393	1.4 MHz	QPSK	1 RB / 0 RB Offset
		19965 to 20385	19965, 20385	3 MHz	QPSK	1 RB / 0 RB Offset
_	Frequency	19975 to 20375	19975, 20375	5 MHz	QPSK	1 RB / 0 RB Offset
1 -	Stability	20000 to 20350	20000, 20350	10 MHz	QPSK	1 RB / 0 RB Offset
		20025 to 20325	20025, 20325	15 MHz	QPSK	1 RB / 0 RB Offset
		20050 to 20300	20050, 20300	20 MHz	QPSK	1 RB / 0 RB Offset
		19957 to 20393	19957, 20175, 20393	1.4 MHz	QPSK, 16QAM, 64QAM	6 RB / 0 RB Offset
		19965 to 20385	19965, 20175, 20385	3 MHz	QPSK, 16QAM, 64QAM	15 RB / 0 RB Offset
	Occupied	19975 to 20375	19975, 20175, 20375	5 MHz	QPSK, 16QAM, 64QAM	25 RB / 0 RB Offset
-	Bandwidth	20000 to 20350	20000, 20175, 20350	10 MHz	QPSK, 16QAM, 64QAM	50 RB / 0 RB Offset
		20025 to 20325	20025, 20175, 20325	15 MHz	QPSK, 16QAM, 64QAM	75 RB / 0 RB Offset
		20050 to 20300	20050, 20175, 20300	20 MHz	QPSK, 16QAM, 64QAM	100 RB / 0 RB Offset
		19957 to 20393	19957, 20175, 20393	1.4 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		19965 to 20385	19965, 20175, 20385	3 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
_	Peak to	19975 to 20375	19975, 20175, 20375	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
	Average Ratio	20000 to 20350	20000, 20175, 20350	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		20025 to 20325	20025, 20175, 20325	15 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		20050 to 20300	20050, 20175, 20300	20 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset



EUT Configure Mode	Test Item	Available Channel	Tested Channel	Channel Bandwidth	Modulation	Mode
			19957	1.4 MHz	QPSK	1 RB / 0 RB Offset
		19957 to 20393	10007	1.4 1011 12	QI OIL	6 RB / 0 RB Offset
		10007 10 20000	20393	1.4 MHz	QPSK	1 RB / 5 RB Offset
			20000	1.1 1011 12	QI OIL	6 RB / 0 RB Offset
			19965	3 MHz	QPSK	1 RB / 0 RB Offset
		19965 to 20385		0 1111 12	Q. O. (15 RB / 0 RB Offset
		10000 10 20000	20385	3 MHz	QPSK	1 RB / 14 RB Offset
			20303	O IVII IZ	QI OIL	15 RB / 0 RB Offset
			19975	5 MHz	QPSK	1 RB / 0 RB Offset
		19975 to 20375	10070	3 1011 12	QI OIL	25 RB / 0 RB Offset
		19979 to 20079	20375	5 MHz	QPSK	1 RB / 24 RB Offset
_	Band Edge		20070	0 1111 12	QI OIL	25 RB / 0 RB Offset
	Dana Lage		20000	10 MHz	QPSK	1 RB / 0 RB Offset
		20000 to 20350 20025 to 20325	20000	10 1011 12	QI OIV	50 RB / 0 RB Offset
			20350	10 MHz	QPSK	1 RB / 49 RB Offset
			20000	10 111112	QI OIL	50 RB / 0 RB Offset
			20025	15 MHz	QPSK	1 RB / 0 RB Offset
				10 10112		75 RB / 0 RB Offset
			20325	15 MHz	QPSK	1 RB / 74 RB Offset
			20020	10 111112	QI OIL	75 RB / 0 RB Offset
			20050	20 MHz	QPSK	1 RB / 0 RB Offset
		20050 to 20300	20000	20 1011 12	QI OIX	100 RB / 0 RB Offset
		20030 to 20300	20300	20 MHz	QPSK	1 RB / 99 RB Offset
			20300	20 1011 12	Qron	100 RB / 0 RB Offset
		19957 to 20393	19957, 20175, 20393	1.4 MHz	QPSK	1 RB / 0 RB Offset
		19965 to 20385	19965, 20175, 20385	3 MHz	QPSK	1 RB / 0 RB Offset
	Conducted	19975 to 20375	19975, 20175, 20375	5 MHz	QPSK	1 RB / 0 RB Offset
	Emission	20000 to 20350	20000, 20175, 20350	10 MHz	QPSK	1 RB / 0 RB Offset
		20025 to 20325	20025, 20175, 20325	15 MHz	QPSK	1 RB / 0 RB Offset
		20050 to 20300	20050, 20175, 20300	20 MHz	QPSK	1 RB / 0 RB Offset
-	Radiated Emission	20050 to 20300	20050, 20175, 20300	20 MHz	QPSK	1 RB / 0 RB Offset

Note: This device was tested under all bandwidths, RB configurations and modulations. The worst case was found in QPSK modulation.



LTE Band 12

EUT Configure Mode	Test Item	em Available Tested Channel Bandwidth		Channel Bandwidth	Modulation	Mode	
		23017 to 23173	23017, 23095, 23173	1.4 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
	ERP	23025 to 23165	23025, 23095, 23165	3 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
-	LKF	23035 to 23155	23035, 23095, 23155	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
		23060 to 23130	23060, 23095, 23130	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
		23017 to 23173	23017, 23173	1.4 MHz	QPSK	1 RB / 0 RB Offset	
	Frequency	23025 to 23165	23025, 23165	3 MHz	QPSK	1 RB / 0 RB Offset	
_	Stability	23035 to 23155	23035, 23155	5 MHz	QPSK	1 RB / 0 RB Offset	
		23060 to 23130	23060, 23130	10 MHz	QPSK	1 RB / 0 RB Offset	
		23017 to 23173	23017, 23095, 23173	1.4 MHz	QPSK, 16QAM, 64QAM	6 RB / 0 RB Offset	
_	Occupied	23025 to 23165	23025, 23095, 23165	3 MHz	QPSK, 16QAM, 64QAM	15 RB / 0 RB Offset	
	Bandwidth	23035 to 23155	23035, 23095, 23155	5 MHz	QPSK, 16QAM, 64QAM	25 RB / 0 RB Offset	
		23060 to 23130	23060, 23095, 23130	10 MHz	QPSK, 16QAM, 64QAM	50 RB / 0 RB Offset	
		23017 to 23173	23017, 23095, 23173	1.4 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
_	Peak to	23025 to 23165	23025, 23095, 23165	3 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
	Average Ratio		23035 to 23155	23035, 23095, 23155	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
		23060 to 23130	23060, 23095, 23130	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
		23017 to 23173	23017	1.4 MHz	QPSK	1 RB / 0 RB Offset 6 RB / 0 RB Offset	
		23017 10 23173	23173	1.4 MHz	QPSK	1 RB / 5 RB Offset 6 RB / 0 RB Offset	
		00005 1- 00405	23025	3 MHz	QPSK	1 RB / 0 RB Offset 15 RB / 0 RB Offset	
		23025 to 23165	23165	3 MHz	QPSK	1 RB / 14 RB Offset 15 RB / 0 RB Offset	
-	Band Edge	00005 / 55 / 5-	23035	5 MHz	QPSK	1 RB / 0 RB Offset 25 RB / 0 RB Offset	
		23035 to 23155	23155	5 MHz	QPSK	1 RB / 24 RB Offset 25 RB / 0 RB Offset	
		22000 1- 22400	23060	10 MHz	QPSK	1 RB / 0 RB Offset 50 RB / 0 RB Offset	
		23060 to 23130	23130	10 MHz	QPSK	1 RB / 49 RB Offset 50 RB / 0 RB Offset	



EUT Configure Mode	Test Item	Available Channel	Tested Channel	Channel Bandwidth	Modulation	Mode	
		23017 to 23173	23017, 23095, 23173	1.4 MHz	QPSK	1 RB / 0 RB Offset	
	Conducted	23025 to 23165	23025, 23095, 23165	3 MHz	QPSK	1 RB / 0 RB Offset	
_	Emission	23035 to 23155	23035, 23095, 23155	5 MHz	QPSK	1 RB / 0 RB Offset	
		23060 to 23130	23060, 23095, 23130	10 MHz	QPSK	1 RB / 0 RB Offset	
-	Radiated Emission	23060 to 23130	23060, 23095, 23130	10 MHz	QPSK	1 RB / 0 RB Offset	

Note: This device was tested under all bandwidths, RB configurations and modulations. The worst case was found in QPSK modulation.

LTE Band 13

EUT Configure Mode	Test Item	Available Channel	Tested Channel	Channel Bandwidth	Modulation	Mode
	ERP	23205 to 23255	23205, 23230, 23255	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
	LINF	23230	23230	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
	Frequency	23205 to 23255	23205, 23255	5 MHz	QPSK	1 RB / 0 RB Offset
-	Stability	23230	23230	10 MHz	QPSK	1 RB / 0 RB Offset
	Occupied	23205 to 23255	23205, 23230, 23255	5 MHz	QPSK, 16QAM, 64QAM	25 RB / 0 RB Offset
-	Bandwidth	23230	23230	10 MHz	QPSK, 16QAM, 64QAM	50 RB / 0 RB Offset
	Peak to	23205 to 23255	23205, 23230, 23255	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
-	Average Ratio	23230	23230	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset
			23205	5 MHz	QPSK	1 RB / 0 RB Offset
		23205 to 23255	23203	J IVII IZ	Qi Si	25 RB / 0 RB Offset
		20200 10 20200	23255	5 MHz	QPSK	1 RB / 24 RB Offset
_	Band Edge		20200	0 WII 12	QI OIL	25 RB / 0 RB Offset
	Dana Lago		23230	10 MHz	QPSK	1 RB / 0 RB Offset
		23230	20200	10 101112	QI OIL	50 RB / 0 RB Offset
		20200	23230	10 MHz	QPSK	1 RB / 49 RB Offset
			20200	10 111112	QI OIL	50 RB / 0 RB Offset
_	Conducted	23205 to 23255	23205, 23230, 23255	5 MHz	QPSK	1 RB / 0 RB Offset
	Emission	23230	23230	10 MHz	QPSK	1 RB / 0 RB Offset
-	Radiated Emission	23230	23230	10 MHz	QPSK	1 RB / 0 RB Offset

Note: This device was tested under all bandwidths, RB configurations and modulations. The worst case was found in QPSK modulation.



LTE Band 17

EUT Configure Mode	Test Item	Available Channel	Tested Channel	Channel Bandwidth	Modulation	Mode	
	ERP	23755 to 23825	23755, 23790, 23825	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
-	ERF	23780 to 23800	23780, 23790, 23800	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
	Frequency	23755 to 23825	23755, 23825	5 MHz	QPSK	1 RB / 0 RB Offset	
-	Stability	23780 to 23800	23780, 23800	10 MHz	QPSK	1 RB / 0 RB Offset	
	Occupied	23755 to 23825	23755, 23790, 23825	5 MHz	QPSK, 16QAM, 64QAM	25 RB / 0 RB Offset	
-	Bandwidth	23780 to 23800	23780, 23790, 23800	10 MHz	QPSK, 16QAM, 64QAM	50 RB / 0 RB Offset	
	Peak to	23755 to 23825	23755, 23790, 23825	5 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
-	Average Ratio	23780 to 23800	23780, 23790, 23800	10 MHz	QPSK, 16QAM, 64QAM	1 RB / 0 RB Offset	
		00755 1- 00005	23755	5 MHz	QPSK	1 RB / 0 RB Offset 25 RB / 0 RB Offset	
			23755 to 23825	23825	5 MHz	QPSK	1 RB / 24 RB Offset 25 RB / 0 RB Offset
-	Band Edge		23780	10 MHz	QPSK	1 RB / 0 RB Offset 50 RB / 0 RB Offset	
		23780 to 23800	23800	10 MHz	QPSK	1 RB / 49 RB Offset 50 RB / 0 RB Offset	
	Conducted	23755 to 23825	23755, 23790, 23825	5 MHz	QPSK	1 RB / 0 RB Offset	
-	Emission	23780 to 23800	23780, 23790, 23800	10 MHz	QPSK	1 RB / 0 RB Offset	
-	Radiated Emission	23780 to 23800	23780, 23790, 23800	10 MHz	QPSK	1 RB / 0 RB Offset	

Note: This device was tested under all bandwidths, RB configurations and modulations. The worst case was found in QPSK modulation.



Test Condition:

Test Item	Environmental Conditions	Input Power	Tested By
ERP / EIRP	25 deg. C, 65 % RH	3.85 Vdc	Karl Lee
Frequency Stability	25 deg. C, 65 % RH	3.85 Vdc	Carlos Chen
Occupied Bandwidth	25 deg. C, 65 % RH	3.85 Vdc	Carlos Chen
Band Edge	25 deg. C, 65 % RH	3.85 Vdc	Carlos Chen
Peak to Average Ratio	25 deg. C, 65 % RH	3.85 Vdc	Carlos Chen
Condcudeted Emission	25 deg. C, 65 % RH	3.85 Vdc	Carlos Chen
Radiated Emission	25 deg. C, 65 % RH	120 Vac, 60 Hz	Karl Lee / Charles Hsiao

3.4 EUT Operating Conditions

The EUT makes a call to the communication simulator. The communication simulator station system controlled a EUT to export maximum output power under transmission mode and specific channel frequency

3.5 General Description of Applied Standards

The EUT is a RF Product. According to the specifications of the manufacturer, it must comply with the requirements of the following standards:

FCC 47 CFR Part 2
FCC 47 CFR Part 27
KDB 971168 D01 Power Meas License Digital Systems v02r02
ANSI/TIA/EIA-603-E 2016
ANSI 63.26-2015

Note: All test items have been performed and recorded as per the above standards.



4 Test Types and Results

4.1 Output Power Measurement

4.1.1 Limits of Output Power Measurement

Fixed, mobile, and portable (hand-held) stations operating in the 1710–1755 MHz band are limited to 1 watt EIRP.

Portable stations (hand-held devices) operating in the 698-787 MHz band are limited to 3 watts ERP

4.1.2 Test Procedures

EIRP / ERP Measurement:

- a. All measurements were done at low, middle and high operational frequency range. RBW and VBW is 5 MHz for WCDMA and 10 MHz for LTE mode.
- b. Substitution method is used for E.I.R.P measurement. In the semi-anechoic chamber, EUT placed on the 0.8 m (below or equal 1 GHz) and/or 1.5 m (above 1 GHz) height of Turn Table, rotated the table around 360 degrees to search the maximum radiation power and receiver antenna shall be rotated vertical and horizontal polarization and moved height from 1 m to 4 m to find the maximum polar radiated power. The "Read Value" is the spectrum reading the maximum power value.
- c. The substitution horn antenna is substituted for EUT at the same position and signals generator export the CW signal to the substitution antenna via a tx cable. Rotated the Turn Table and moved receiving antenna to find the maximum radiation power. Adjust output power level of S.G to get a Value of spectrum reading equal to "Read Value" of step b. Record the power level of S.G.
- d. EIRP = Output power level of S.G TX cable loss + Antenna gain of substitution horn.E.R.P power can be calculated form E.I.R.P power by subtracting the gain of dipole, E.R.P power = E.I.P.R power 2.15 dBi.

Conducted Power Measurement:

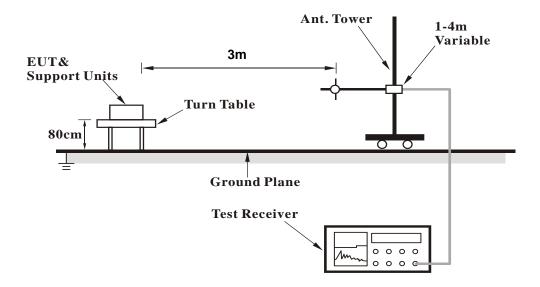
- a. The EUT was set up for the maximum power with WCDMA and LTE link data modulation and link up with simulator.
- b. Set the EUT to transmit under low, middle and high channel and record the power level shown on simulator.



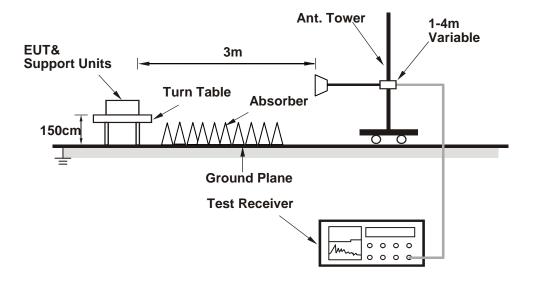
4.1.3 Test Setup

EIRP / ERP Measurement:

<Radiated Emission below or equal 1 GHz>



<Radiated Emission above 1 GHz>



For the actual test configuration, please refer to the attached file (Test Setup Photo).

Conducted Power Measurement:





4.1.4 Test Results

Conducted Output Power (dBm)

Band		WCDMA IV	
Channel	1312	1413	1513
Frequency (MHz)	1712.4	1732.6	1752.6
RMC 12.2K	23.31	23.39	23.30
HSDPA Subtest-1	22.27	22.35	22.26
HSDPA Subtest-2	22.30	22.38	22.29
HSDPA Subtest-3	22.10	22.18	22.09
HSDPA Subtest-4	22.09	22.17	22.08
HSUPA Subtest-1	22.33	22.32	22.32
HSUPA Subtest-2	20.30	20.38	20.29
HSUPA Subtest-3	21.30	21.38	21.29
HSUPA Subtest-4	20.33	20.27	20.32
HSUPA Subtest-5	22.32	22.33	22.31



							LTE Ban	d 4						
				QP	SK				QAM			640	QAM	
BW (MHz)	RB Size	RB Offset	Low CH 20050 1720.0	Mid CH 20175 1732.5	High CH 20300 1745.0	3GPP MPR (dB)	Low CH 20050 1720.0	Mid CH 20175 1732.5	High CH 20300 1745.0	3GPP MPR (dB)	Low CH 20050 1720.0	Mid CH 20175 1732.5	High CH 20300 1745.0	3GPP MPR (dB)
	1	0	MHz	MHz	MHz	0	MHz	MHz 22.50	MHz		MHz	MHz	MHz	, ,
	1	50	23.41	23.52 23.32	23.61 23.41	0	22.39 22.19	22.30	22.59 22.39	1	21.46 21.25	21.58 21.37	21.56 21.35	2
	1	99	23.23	23.34	23.43	0	22.21	22.32	22.41	1	21.17	21.42	21.32	2
20	50	0	22.42	22.53	22.62	1	21.40	21.51	21.60	2	20.30	20.51	20.63	3
	50	25	22.35	22.46	22.55	1	21.33	21.44	21.53	2	20.22	20.23	20.37	3
	50	50	22.18	22.29	22.38	1	21.16	21.27	21.36	2	20.12	20.39	20.41	3
	100	0	22.29	22.40	22.49	1	21.27	21.38	21.47	2	20.13	20.25	20.44	3
			Low CH	QP Mid CH	SK Ulark CU		Law CII	160 Mid CH	QAM	1	Low CH	Mid CH	QAM	ı
BW	RB	RB	20025	20175	High CH 20325	3GPP	Low CH 20025	20175	High CH 20325	3GPP	20025	20175	High CH 20325	3GPP
(MHz)	Size	Offset	1717.5	1732.5	1747.5	MPR (dB)	1717.5	1732.5	1747.5	MPR (dB)	1717.5	1732.5	1747.5	MPR (dB)
	1	0	MHz 23.39	MHz 23.50	MHz	, ,	MHz	MHz 22.48	MHz 22.57	1	MHz 21.37	MHz	MHz 21.57	2
	1	37	23.19	23.30	23.59	0	22.37 22.17	22.48	22.37	1	21.37	21.45 21.33	21.57	2
	1	74	23.21	23.32	23.41	0	22.17	22.30	22.39	1	21.15	21.29	21.45	2
15	36	0	22.40	22.51	22.60	1	21.38	21.49	21.58	2	20.32	20.44	20.63	3
	36	19	22.33	22.44	22.53	1	21.31	21.42	21.51	2	20.11	20.33	20.47	3
I	36	39	22.16	22.27	22.36	1	21.14	21.25	21.34	2	20.22	20.24	20.39	3
	75	0	22.27	22.38	22.47	1	21.25	21.36	21.45	2	20.28	20.40	20.35	3
			1,611		SK Ulark CU		1		QAM		1 611		QAM	
BW	RB	RB	Low CH 20000	Mid CH 20175	High CH 20350	3GPP	Low CH 20000	Mid CH 20175	High CH 20350	3GPP	Low CH 20000	Mid CH 20175	High CH 20350	3GPP
(MHz)	Size	Offset	1715.0	1732.5	1750.0	MPR (dB)	1715.0	1732.5	1750.0	MPR (dB)	1715.0	1732.5	1750.0	MPR (dB)
			MHz	MHz	MHz	, ,	MHz	MHz	MHz		MHz	MHz	MHz	, ,
	1	0	23.35	23.46	23.55	0	22.33	22.44	22.53	1	21.41	21.59	21.55	2
	1	24 49	23.15	23.26 23.28	23.35	0	22.13 22.15	22.24 22.26	22.33 22.35	1	21.13 21.13	21.22 21.38	21.35 21.38	2
10	25	0	22.36	22.47	22.56	1	21.34	21.45	21.54	2	20.37	20.60	20.53	3
	25	12	22.29	22.40	22.49	1	21.27	21.38	21.47	2	20.19	20.25	20.38	3
	25	25	22.12	22.23	22.32	1	21.10	21.21	21.30	2	20.18	20.30	20.33	3
	50	0	22.23	22.34	22.43	1	21.21	21.32	21.41	2	20.26	20.28	20.38	3
					SK				QAM	-			QAM	-
BW	RB	RB	Low CH 19975	Mid CH 20175	High CH 20375	3GPP	Low CH 19975	Mid CH 20175	High CH 20375	3GPP	Low CH 19975	Mid CH 20175	High CH 20375	3GPP
(MHz)	Size	Offset	1712.5	1732.5	1752.5	MPR	1712.5	1732.5	1752.5	MPR	1712.5	1732.5	1752.5	MPR
			MHz	MHz	MHz	(dB)	MHz	MHz	MHz	(dB)	MHz	MHz	MHz	(dB)
	1	0	23.34	23.45	23.54	0	22.32	22.43	22.52	1	21.31	21.55	21.49	2
	1	12 24	23.14	23.25 23.27	23.34 23.36	0	22.12 22.14	22.23 22.25	22.32 22.34	1	21.10 21.27	21.32 21.41	21.41 21.34	2
5	12	0	22.35	22.46	22.55	1	21.33	21.44	21.53	2	20.32	20.44	20.62	3
	12	6	22.28	22.39	22.48	1	21.26	21.37	21.46	2	20.22	20.26	20.40	3
	12	13	22.11	22.22	22.31	1	21.09	21.20	21.29	2	20.11	20.29	20.39	3
	25	0	22.22	22.33	22.42	1	21.20	21.31	21.40	2	20.24	20.33	20.37	3
					SK				QAM	1			QAM	ı
BW	RB	RB	Low CH 19965	Mid CH 20175	High CH 20385	3GPP	Low CH 19965	Mid CH 20175	High CH 20385	3GPP	Low CH 19965	Mid CH 20175	High CH 20385	3GPP
(MHz)	Size	Offset	1711.5	1732.5	1753.5	MPR	1711.5	1732.5	1753.5	MPR	1711.5	1732.5	1753.5	MPR (dB)
			MHz	MHz	MHz	(dB)	MHz	MHz	MHz	(dB)	MHz	MHz	MHz	
]	1	0	23.30	23.41	23.50	0	22.28	22.39	22.48	1	21.24	21.52	21.56	2
]	1	7 14	23.10	23.21	23.30	0	22.08 22.10	22.19 22.21	22.28 22.30	1	21.20 21.17	21.27 21.26	21.32 21.35	2
3	8	0	22.31	23.23	23.32	1	21.29	21.40	21.49	2	20.33	20.37	20.56	3
	8	3	22.24	22.35	22.44	1	21.22	21.33	21.42	2	20.23	20.26	20.38	3
	8	7	22.07	22.18	22.27	1	21.05	21.16	21.25	2	20.22	20.17	20.35	3
		0	22.18	22.29	22.38	1	21.16	21.27	21.36	2	20.20	20.25	20.33	3
	15			OP	SK				QAM				MAG	
	15						Low CH	Mid CH	High CH	3GPP	Low CH	Mid CH	High CH	3GPP
BW	RB	RB	Low CH 19957	Mid CH	High CH	3GPP		20175			19957	20175	20303	
BW (MHz)		RB Offset	Low CH 19957 1710.7			MPR	19957 1710.7	20175 1732.5	20393 1754.3	MPR	19957 1710.7	20175 1732.5	20393 1754.3	MPR
	RB Size	Offset	19957 1710.7 MHz	Mid CH 20175 1732.5 MHz	High CH 20393 1754.3 MHz	MPR (dB)	19957 1710.7 MHz	1732.5 MHz	20393 1754.3 MHz	MPR (dB)	1710.7 MHz	1732.5 MHz	1754.3 MHz	(dB)
	RB Size	Offset O	19957 1710.7 MHz 23.29	Mid CH 20175 1732.5 MHz 23.40	High CH 20393 1754.3 MHz 23.49	MPR (dB)	19957 1710.7 MHz 22.27	1732.5 MHz 22.38	20393 1754.3 MHz 22.47	MPR (dB)	1710.7 MHz 21.25	1732.5 MHz 21.43	1754.3 MHz 21.45	(dB)
	RB Size	Offset 0 2	19957 1710.7 MHz 23.29 23.09	Mid CH 20175 1732.5 MHz 23.40 23.20	High CH 20393 1754.3 MHz 23.49 23.29	MPR (dB) 0 0	19957 1710.7 MHz 22.27 22.07	1732.5 MHz 22.38 22.18	20393 1754.3 MHz 22.47 22.27	MPR (dB)	1710.7 MHz 21.25 21.10	1732.5 MHz 21.43 21.17	1754.3 MHz 21.45 21.44	(dB) 2 2
(MHz)	RB Size	0 2 5	19957 1710.7 MHz 23.29 23.09 23.11	Mid CH 20175 1732.5 MHz 23.40 23.20 23.22	High CH 20393 1754.3 MHz 23.49 23.29 23.31	MPR (dB) 0 0 0	19957 1710.7 MHz 22.27 22.07 22.09	1732.5 MHz 22.38 22.18 22.20	20393 1754.3 MHz 22.47 22.27 22.29	MPR (dB) 1 1 1	1710.7 MHz 21.25 21.10 21.10	1732.5 MHz 21.43 21.17 21.18	1754.3 MHz 21.45 21.44 21.27	(dB) 2 2 2
	RB Size 1 1 1 1 3	0 2 5 0	19957 1710.7 MHz 23.29 23.09 23.11 23.10	Mid CH 20175 1732.5 MHz 23.40 23.20 23.22 23.22	High CH 20393 1754.3 MHz 23.49 23.29 23.31 23.30	MPR (dB) 0 0 0 0	19957 1710.7 MHz 22.27 22.07 22.09 22.08	1732.5 MHz 22.38 22.18 22.20 22.19	20393 1754.3 MHz 22.47 22.27 22.29 22.28	MPR (dB) 1 1 1 1	1710.7 MHz 21.25 21.10 21.10 21.39	1732.5 MHz 21.43 21.17 21.18 21.39	1754.3 MHz 21.45 21.44 21.27 21.63	(dB) 2 2 2 2
(MHz)	RB Size	0 2 5	19957 1710.7 MHz 23.29 23.09 23.11	Mid CH 20175 1732.5 MHz 23.40 23.20 23.22	High CH 20393 1754.3 MHz 23.49 23.29 23.31	MPR (dB) 0 0 0	19957 1710.7 MHz 22.27 22.07 22.09	1732.5 MHz 22.38 22.18 22.20	20393 1754.3 MHz 22.47 22.27 22.29	MPR (dB) 1 1 1	1710.7 MHz 21.25 21.10 21.10	1732.5 MHz 21.43 21.17 21.18	1754.3 MHz 21.45 21.44 21.27	(dB) 2 2 2



						L	TE Ban	d 12							
				QP	SK	_			QAM			640	QAM .		
BW (MHz)	RB Size	RB Offset	Low CH 23060	Mid CH 23095	High CH 23130	3GPP MPR	Low CH 23060	Mid CH 23095	High CH 23130	3GPP MPR	Low CH 23060	Mid CH 23095	High CH 23130	3GPP MPR	
(141112)	3126	Oliset	704.0 MHz	707.5 MHz	711.0 MHz	(dB)	704.0 MHz	707.5 MHz	711.0 MHz	(dB)	704.0 MHz	707.5 MHz	711.0 MHz	(dB)	
	1	0	23.37	23.39	23.33	0	22.35	22.37	22.31	1	21.38	21.41	21.32	2	
	1	24	23.28	23.30	23.24	0	22.26	22.28	22.22	1	21.36	21.28	21.28	2	
	1	49	23.14	23.16	23.10	0	22.12	22.14	22.08	1	21.17	21.17	21.22	2	
10	25	0	22.30	22.32	22.26	1	21.28	21.30	21.24	2	20.39	20.39	20.33	3	
	25	12	22.28	22.30	22.24	1	21.26	21.28	21.22	2	20.28	20.36	20.37	3	
	25	25	22.27	22.29	22.23	1	21.25	21.27	21.21	2	20.16	20.25	20.08	3	
	50	0	22.15	22.17	22.11	1	21.13	21.15	21.09	2	20.14	20.27	20.09	3	
				QP			16QAM					QAM			
BW (MHz)	RB Size	RB Offset	Low CH 23035	Mid CH 23095	High CH 23155	3GPP MPR	Low CH 23035	Mid CH 23095	High CH 23155	3GPP MPR	Low CH 23035	Mid CH 23095	High CH 23155	3GPP MPR	
(WITZ)	Size	Oliset	701.5 MHz	707.5 MHz	713.5 MHz	(dB)	701.5 MHz	707.5 MHz	713.5 MHz	(dB)	701.5 MHz	707.5 MHz	713.5 MHz	(dB)	
	1	0	23.33	23.35	23.29	0	22.31	22.33	22.27	1	21.33	21.39	21.29	2	
	1	12	23.24	23.26	23.20	0	22.22	22.24	22.18	1	21.29	21.31	21.32	2	
	1	24	23.10	23.12	23.06	0	22.08	22.10	22.04	1	21.12	21.29	21.10	2	
5	12	0	22.26	22.28	22.22	1	21.24	21.26	21.20	2	20.43	20.48	20.42	3	
	12	6	22.24	22.26	22.20	1	21.22	21.24	21.18	2	20.39	20.43	20.32	3	
	12	13	22.23	22.25	22.19	1	21.21	21.23	21.17	2	20.15	20.25	20.10	3	
	25	0	22.11	22.13	22.07	1	21.09	21.11	21.05	2	20.23	20.21	20.16	3	
				QP					16QAM			64QAM			
BW (MHz)	RB Size	RB Offset	Low CH 23025	Mid CH 23095	High CH 23165	3GPP MPR	Low CH 23025	Mid CH 23095	High CH 23165	3GPP MPR	Low CH 23025	Mid CH 23095	High CH 23165	3GPP MPR	
(141112)	Oize	Oliset	700.5 MHz	707.5 MHz	714.5 MHz	(dB)	700.5 MHz	707.5 MHz	714.5 MHz	(dB)	700.5 MHz	707.5 MHz	714.5 MHz	(dB)	
	1	0	23.31	23.33	23.27	0	22.29	22.31	22.25	1	21.38	21.50	21.28	2	
	1	7	23.22	23.24	23.18	0	22.20	22.22	22.16	1	21.39	21.27	21.31	2	
	1	14	23.08	23.10	23.04	0	22.06	22.08	22.02	1	21.28	21.12	21.17	2	
3	8	0	22.24	22.26	22.20	1	21.22	21.24	21.18	2	20.33	20.54	20.45	3	
	8	3	22.22	22.24	22.18	1	21.20	21.22	21.16	2	20.30	20.35	20.23	3	
	8	7	22.21	22.23	22.17	1	21.19	21.21	21.15	2	20.19	20.19	20.14	3	
	15	0	22.09	22.11	22.05	1	21.07	21.09	21.03	2	20.16	20.18	20.06	3	
				QP					QAM				QAM		
BW	RB	RB	Low CH 23017	Mid CH 23095	High CH 23173	3GPP	Low CH 23017	Mid CH 23095	High CH 23173	3GPP	Low CH 23017	Mid CH 23095	High CH 23173	3GPP	
(MHz)	Size	Offset	699.7	707.5	715.3	MPR	699.7	707.5	715.3	MPR	699.7	707.5	715.3	MPR	
			MHz	MHz	MHz	(dB)	MHz	MHz	MHz	(dB)	MHz	MHz	MHz	(dB)	
	1	0	23.30	23.32	23.26	0	22.28	22.30	22.24	1	21.41	21.46	21.36	2	
	1	2	23.21	23.23	23.17	0	22.19	22.21	22.15	1	21.25	21.36	21.22	2	
	1	5	23.07	23.09	23.03	0	22.05	22.07	22.01	1	21.09	21.11	21.19	2	
			00.40	23.15	23.09	0	22.11	22.13	22.07	1	21.40	21.53	21.36	2	
1.4	3	0	23.13												
1.4	3	1	23.11	23.13	23.07	0	22.09	22.11	22.05	1	21.39	21.40	21.32	2	
1.4	3	_				0 0 1	22.09 22.08 21.06	22.11 22.10 21.08	22.05 22.04 21.02	1 1 2	21.39 21.28 20.24	21.40 21.28 20.11	21.32 21.22 20.06	2 2 3	



						L	TE Ban	d 13						
				QP	SK			160	QAM			640	QAM	
BW (MHz)	RB Size	RB Offset		Mid CH 23230		3GPP MPR		Mid CH 23230		3GPP MPR		Mid CH 23230		3GPP MPR
(WITZ)	Size	Oliset		782.0 MHz		(dB)		782.0 MHz		(dB)		782.0 MHz		(dB)
	1	0		23.23		0		22.21		1		21.24		2
	1	24		23.12		0		22.10		1		21.20		2
	1	49		23.05		0		22.03		1		21.15		2
10	25	0		22.22		1		21.20		2		20.24		3
	25	12		22.06		1		21.04		2		20.11		3
	25	25		22.04		1		21.02		2		20.08		3
	50	0		21.98		1		20.96		2		20.05		3
				QP	SK		16QAM				640	QAM		
BW (MHz)	RB Size	RB Offset	Low CH 23205	Mid CH 23230	High CH 23255	3GPP MPR	Low CH 23205	Mid CH 23230	High CH 23255	3GPP MPR	Low CH 23205	Mid CH 23230	High CH 23255	3GPP MPR
(141112)	Size	Oliset	779.5 MHz	782.0 MHz	784.5 MHz	(dB)	779.5 MHz	782.0 MHz	784.5 MHz	(dB)	779.5 MHz	782.0 MHz	784.5 MHz	(dB)
	1	0	23.18	23.21	23.19	0	22.15	22.18	22.16	1	21.13	21.25	21.29	2
	1	12	23.07	23.10	23.08	0	22.04	22.07	22.05	1	21.22	21.09	21.05	2
	1	24	23.00	23.03	23.01	0	21.97	22.00	21.98	1	20.98	21.06	21.01	2
5	12	0	22.17	22.20	22.18	1	21.14	21.17	21.15	2	20.21	20.36	20.27	3
	12	6	22.01	22.04	22.02	1	20.98	21.01	20.99	2	20.03	20.07	20.13	3
	12	13	21.99	22.02	22.00	1	20.96	20.99	20.97	2	20.04	20.02	20.11	3
	25	0	21.93	21.96	21.94	1	20.90	20.93	20.91	2	20.04	20.15	20.04	3

	LTE Band 17													
				QP	SK				QAM			640	QAM	
BW (MHz)	RB Size	RB Offset	Low CH 23780	Mid CH 23790	High CH 23800	3GPP MPR	Low CH 23780	Mid CH 23790	High CH 23800	3GPP MPR	Low CH 23780	Mid CH 23790	High CH 23800	3GPP MPR
(WITTZ)	Size	Oliset	709.0 MHz	710.0 MHz	711.0 MHz	(dB)	709.0 MHz	710.0 MHz	711.0 MHz	(dB)	709.0 MHz	710.0 MHz	711.0 MHz	(dB)
	1	0	23.24	23.40	23.39	0	22.20	22.36	22.35	1	21.29	21.39	21.47	2
	1	24	23.23	23.39	23.38	0	22.19	22.35	22.34	1	21.38	21.44	21.46	2
	1	49	23.16	23.32	23.31	0	22.12	22.28	22.27	1	21.11	21.45	21.35	2
10	25	0	22.23	22.39	22.38	1	21.19	21.35	21.34	2	20.37	20.39	20.54	3
	25	12	22.08	22.24	22.23	1	21.04	21.20	21.19	2	20.23	20.51	20.50	3
	25	25	22.02	22.18	22.17	1	20.98	21.14	21.13	2	20.13	20.46	20.26	3
	50	0	21.90	22.06	22.05	1	20.86	21.02	21.01	2	20.16	20.40	20.30	3
			QPSK				16QAM			=		640	QAM	
BW (MHz)	RB Size	RB Offset	Low CH 23755	Mid CH 23790	High CH 23825	3GPP MPR	Low CH 23755	Mid CH 23790	High CH 23825	3GPP MPR	Low CH 23755	Mid CH 23790	High CH 23825	3GPP MPR
(WII 12)	Size	Oliset	706.5 MHz	710.0 MHz	713.5 MHz	(dB)	706.5 MHz	710.0 MHz	713.5 MHz	(dB)	706.5 MHz	710.0 MHz	713.5 MHz	(dB)
	1	0	23.21	23.37	23.36	0	22.17	22.33	22.32	1	21.31	21.48	21.49	2
	1	12	23.20	23.36	23.35	0	22.16	22.32	22.31	1	21.30	21.45	21.41	2
	1	24	23.13	23.29	23.28	0	22.09	22.25	22.24	1	21.21	21.47	21.37	2
5	12	0	22.20	22.36	22.35	1	21.16	21.32	21.31	2	20.35	20.43	20.49	3
	12	6	22.05	22.21	22.20	1	21.01	21.17	21.16	2	20.20	20.52	20.40	3
	12	13	21.99	22.15	22.14	1	20.95	21.11	21.10	2	20.14	20.43	20.34	3
	25	0	21.87	22.03	22.02	1	20.83	20.99	20.98	2	20.21	20.32	20.33	3



ERP Power (dBm)

LTE Band 12													
	Channel Bandwidth: 1.4 MHz / QPSK												
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)						
	23017	699.7	-13.06	32.719	17.51	56.35							
	23095	707.5	-13.09	32.736	17.50	56.18	Н						
X	23173	715.3	-12.92	32.591	17.52	56.51							
_ ^	23017	699.7	-16.08	32.69	14.46	27.93							
	23095	707.5	-16.20	32.81	14.46	27.93	V						
	23173	715.3	-16.07	32.74	14.52	28.31							
		C	hannel Ban	dwidth: 1.4 MHz	:/16QAM								
	23017	699.7	-14.05	32.719	16.52	44.86							
	23095	707.5	-14.03	32.736	16.56	45.25	Н						
X	23173	715.3	-13.90	32.591	16.54	45.09							
^	23017	699.7	-17.00	32.69	13.54	22.59							
	23095	707.5	-17.12	32.81	13.54	22.59	V						
	23173	715.3	-17.08	32.74	13.51	22.44							
		C	hannel Ban	dwidth: 1.4 MHz	: / 64QAM								
	23017	699.7	-14.85	32.719	15.72	37.28							
	23095	707.5	-14.97	32.736	15.62	36.45	Н						
X	23173	715.3	-14.65	32.591	15.79	37.92							
^	23017	699.7	-17.96	32.69	12.58	18.13							
	23095	707.5	-17.86	32.81	12.80	19.07	V						
	23173	715.3	-17.82	32.74	12.78	18.95							



LTE Band 12												
Channel Bandwidth: 3 MHz / QPSK												
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)					
	23025	700.5	-13.02	32.719	17.55	56.87						
	23095	707.5	-13.04	32.736	17.55	56.83	Н					
Х	23165	714.5	-12.91	32.591	17.53	56.64						
^	23025	700.5	-16.00	32.69	14.54	28.44						
	23095	707.5	-16.20	32.81	14.46	27.93	V					
	23165	714.5	-16.08	32.74	14.51	28.25						
			Channel Ba	ndwidth: 3 MHz	/ 16QAM							
	23025	700.5	-14.00	32.719	16.57	45.38						
	23095	707.5	-14.12	32.736	16.47	44.32	Н					
V	23165	714.5	-13.94	32.591	16.50	44.68						
Х	23025	700.5	-17.12	32.69	13.42	21.98						
	23095	707.5	-17.15	32.81	13.51	22.44	V					
	23165	714.5	-17.08	32.74	13.51	22.44						
			Channel Ba	ndwidth: 3 MHz	/ 64QAM							
	23025	700.5	-14.66	32.719	15.91	39.00						
	23095	707.5	-14.86	32.736	15.73	37.39	Н					
V	23165	714.5	-14.86	32.591	15.58	36.16						
Х	23025	700.5	-18.24	32.69	12.30	16.98						
	23095	707.5	-18.53	32.81	12.13	16.35	V					
	23165	714.5	-18.26	32.74	12.33	17.09						



LTE Band 12											
Channel Bandwidth: 5 MHz / QPSK											
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)				
	23035	701.5	-13.02	32.719	17.55	56.87					
	23095	707.5	-13.03	32.736	17.56	56.96	Н				
Х	23155	713.5	-12.92	32.591	17.52	56.51					
^	23035	701.5	-16.05	32.69	14.49	28.12					
	23095	707.5	-16.12	32.81	14.54	28.44	V				
	23155	713.5	-16.11	32.74	14.48	28.05					
	Channel Bandwidth: 5 MHz / 16QAM										
	23035	701.5	-13.99	32.719	16.58	45.49					
	23095	707.5	-14.11	32.736	16.48	44.42	Н				
X	23155	713.5	-13.90	32.591	16.54	45.09					
^	23035	701.5	-17.02	32.69	13.52	22.49					
	23095	707.5	-17.13	32.81	13.53	22.54	V				
	23155	713.5	-17.10	32.74	13.49	22.34					
			Channel Ba	ndwidth: 5 MHz	/ 64QAM						
	23035	701.5	-14.70	32.719	15.87	38.67					
	23095	707.5	-14.90	32.736	15.69	37.08	Н				
X	23155	713.5	-14.69	32.591	15.75	37.61					
^	23035	701.5	-17.89	32.69	12.65	18.41					
	23095	707.5	-17.96	32.81	12.70	18.63	V				
	23155	713.5	-17.86	32.74	12.73	18.75					



LTE Band 12												
Channel Bandwidth: 10 MHz / QPSK												
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)					
	23060	704.0	-13.02	32.727	17.56	56.98						
	23095	707.5	-12.98	32.739	17.61	57.66	Н					
Х	23130	711.0	-13.00	32.728	17.58	57.25						
^	23060	704.0	-16.08	32.75	14.52	28.31						
	23095	707.5	-16.13	32.81	14.53	28.38	V					
	23130	711.0	-16.11	32.84	14.58	28.71						
		C	Channel Bar	ndwidth: 10 MHz	/ 16QAM							
	23060	704.0	-14.02	32.727	16.56	45.26						
	23095	707.5	-14.08	32.739	16.51	44.76	Н					
Х	23130	711.0	-13.95	32.728	16.63	46.00						
^	23060	704.0	-17.21	32.75	13.39	21.83						
	23095	707.5	-17.16	32.81	13.50	22.39	V					
	23130	711.0	-17.20	32.84	13.49	22.34						
		C	Channel Bar	ndwidth: 10 MHz	/ 64QAM							
	23060	704.0	-15.21	32.727	15.37	34.41						
	23095	707.5	-15.88	32.739	14.71	29.58	Н					
X	23130	711.0	-15.48	32.728	15.10	32.34						
۸	23060	704.0	-17.87	32.75	12.73	18.75						
	23095	707.5	-17.92	32.81	12.74	18.79	V					
	23130	711.0	-17.78	32.84	12.91	19.54						



LTE Band 13											
Channel Bandwidth: 5 MHz / QPSK											
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)				
	23205	779.5	-13.09	32.771	17.53	56.64					
	23230	782.0	-13.07	32.741	17.52	56.51	Н				
X	23255	784.5	-13.15	32.854	17.55	56.94					
^	23205	779.5	-15.76	32.5	14.59	28.77					
	23230	782.0	-15.82	32.52	14.55	28.51	V				
	23255	784.5	-15.96	32.62	14.51	28.25					
	Channel Bandwidth: 5 MHz / 16QAM										
	23205	779.5	-14.12	32.771	16.50	44.68					
	23230	782.0	-14.08	32.741	16.51	44.78	Н				
	23255	784.5	-14.16	32.854	16.54	45.12					
X	23205	779.5	-16.82	32.5	13.53	22.54					
	23230	782.0	-16.83	32.52	13.54	22.59	V				
	23255	784.5	-16.98	32.62	13.49	22.34					
			Channel Ba	ndwidth: 5 MHz	/ 64QAM						
	23205	779.5	-15.23	32.771	15.39	34.60					
	23230	782.0	-15.02	32.741	15.57	36.07	Н				
	23255	784.5	-14.86	32.854	15.85	38.43					
X	23205	779.5	-17.52	32.5	12.83	19.19					
	23230	782.0	-17.62	32.52	12.75	18.84	V				
	23255	784.5	-17.95	32.62	12.52	17.86					



	LTE Band 13											
	Channel Bandwidth: 10 MHz / QPSK											
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)					
Х	23230	782.0	-13.00	32.737	17.59	57.37	Н					
^	23230	782.0	-15.76	32.52	14.61	28.91	V					
		(Channel Bar	ndwidth: 10 MHz	/ 16QAM							
Х	23230	782.0	-13.96	32.737	16.63	45.99	Н					
^	23230	782.0	-16.72	32.52	13.65	23.17	V					
	Channel Bandwidth: 10 MHz / 64QAM											
V	23230	782.0	-14.62	32.737	15.97	39.51	Н					
Х	23230	782.0	-17.56	32.52	12.81	19.10	V					



LTE Band 17											
Channel Bandwidth: 5 MHz / QPSK											
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)				
	23755	706.5	-7.50	32.719	23.07	202.72					
	23790	710.0	-7.53	32.736	23.06	202.12	Н				
X	23825	713.5	-7.41	32.591	23.03	200.96					
_ ^	23755	706.5	-12.49	32.69	18.05	63.83					
	23790	710.0	-12.56	32.81	18.10	64.57	V				
	23825	713.5	-12.56	32.74	18.03	63.53					
			Channel Ba	ndwidth: 5 MHz	/ 16QAM						
	23755	706.5	-13.03	32.719	17.54	56.74					
	23790	710.0	-13.08	32.736	17.51	56.31	Н				
	23825	713.5	-12.86	32.591	17.58	57.29					
X	23755	706.5	-16.00	32.69	14.54	28.44					
	23790	710.0	-16.08	32.81	14.58	28.71	V				
	23825	713.5	-16.07	32.74	14.52	28.31					
			Channel Ba	ndwidth: 5 MHz	/ 64QAM						
	23755	706.5	-13.98	32.719	16.59	45.59					
	23790	710.0	-13.85	32.736	16.74	47.16	Н				
V	23825	713.5	-13.65	32.591	16.79	47.76					
Х	23755	706.5	-16.75	32.69	13.79	23.93					
	23790	710.0	-16.88	32.81	13.78	23.88	V				
	23825	713.5	-16.69	32.74	13.90	24.55					



LTE Band 17											
Channel Bandwidth: 10 MHz / QPSK											
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	ERP (dBm)	ERP (mW)	Polarization (H/V)				
	23780	709.0	-7.53	32.727	23.05	201.70					
	23790	710.0	-7.44	32.739	23.15	206.49	Н				
X	23800	711.0	-7.56	32.728	23.02	200.35					
^	23780	709.0	-12.58	32.75	18.02	63.39					
	23790	710.0	-12.52	32.81	18.14	65.16	V				
	23800	711.0	-12.53	32.84	18.16	65.46					
	Channel Bandwidth: 10 MHz / 16QAM										
	23780	709.0	-13.09	32.727	17.49	56.07					
	23790	710.0	-13.07	32.739	17.52	56.48	Н				
X	23800	711.0	-13.06	32.728	17.52	56.47					
^	23780	709.0	-16.08	32.75	14.52	28.31					
	23790	710.0	-16.16	32.81	14.50	28.18	V				
	23800	711.0	-16.20	32.84	14.49	28.12					
		(Channel Bar	ndwidth: 10 MHz	/ 64QAM						
	23780	709.0	-13.87	32.727	16.71	46.90					
	23790	710.0	-13.77	32.739	16.82	48.08	Н				
X	23800	711.0	-13.96	32.728	16.62	45.91					
^	23780	709.0	-16.86	32.75	13.74	23.68					
	23790	710.0	-16.95	32.81	13.71	23.52	V				
	23800	711.0	-16.86	32.84	13.83	24.17					



EIRP Power (dBm)

	WCDMA										
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)				
	1312	1712.4	-20.43	42.49	22.06	160.51					
	1413	1732.6	-20.24	42.33	22.09	161.70	Н				
X	1513	1752.6	-20.07	42.10	22.03	159.59					
^	1312	1712.4	-25.93	42.99	17.06	50.82					
	1413	1732.6	-25.63	42.74	17.11	51.40	V				
	1513	1752.6	-25.20	42.21	17.01	50.23					

LTE Band 4								
Channel Bandwidth: 1.4 MHz / QPSK								
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)	
X	19957	1710.7	-20.42	42.49	22.07	160.88		
	20175	1732.5	-20.31	42.33	22.02	159.11	Н	
	20393	1754.3	-20.09	42.10	22.01	158.85		
^	19957	1710.7	-25.89	42.99	17.10	51.29		
	20175	1732.5	-25.70	42.74	17.04	50.58	V	
	20393	1754.3	-25.12	42.21	17.09	51.17		
Channel Bandwidth: 1.4 MHz / 16QAM								
	19957	1710.7	-21.48	42.49	21.01	126.04	Н	
	20175	1732.5	-21.30	42.33	21.03	126.68		
	20393	1754.3	-21.06	42.10	21.04	127.06		
Х	19957	1710.7	-26.93	42.99	16.06	40.36		
	20175	1732.5	-26.64	42.74	16.10	40.74	V	
	20393	1754.3	-26.14	42.21	16.07	40.46		
Channel Bandwidth: 1.4 MHz / 64QAM								
Х	19957	1710.7	-22.14	42.49	20.35	108.27	Н	
	20175	1732.5	-21.98	42.33	20.35	108.32		
	20393	1754.3	-21.87	42.10	20.23	105.44		
	19957	1710.7	-27.24	42.99	15.75	37.58		
	20175	1732.5	-27.62	42.74	15.12	32.51	V	
	20393	1754.3	-27.14	42.21	15.07	32.14		



LTE Band 4								
Channel Bandwidth: 3 MHz / QPSK								
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)	
Х	19965	1711.5	-20.42	42.49	22.07	160.88		
	20175	1732.5	-20.23	42.33	22.10	162.07	Н	
	20385	1753.5	-20.08	42.10	22.02	159.22		
	19965	1711.5	-25.92	42.99	17.07	50.93		
	20175	1732.5	-25.60	42.74	17.14	51.76	V	
	20385	1753.5	-25.21	42.21	17.00	50.12		
			Channel Ba	ndwidth: 3 MHz	/ 16QAM			
	19965	1711.5	-21.42	42.49	21.07	127.79	Н	
X	20175	1732.5	-21.30	42.33	21.03	126.68		
	20385	1753.5	-21.07	42.10	21.03	126.77		
	19965	1711.5	-26.90	42.99	16.09	40.64		
	20175	1732.5	-26.64	42.74	16.10	40.74	V	
	20385	1753.5	-26.20	42.21	16.01	39.90		
			Channel Ba	ndwidth: 3 MHz	/ 64QAM			
Х	19965	1711.5	-22.12	42.49	20.37	108.77	н	
	20175	1732.5	-21.89	42.33	20.44	110.59		
	20385	1753.5	-21.78	42.10	20.32	107.65	_	
	19965	1711.5	-27.21	42.99	15.78	37.84		
	20175	1732.5	-27.51	42.74	15.23	33.34	V	
	20385	1753.5	-27.01	42.21	15.20	33.11		



LTE Band 4								
Channel Bandwidth: 5 MHz / QPSK								
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)	
Х	19975	1712.5	-20.49	42.49	22.00	158.31		
	20175	1732.5	-20.28	42.33	22.05	160.21	Н	
	20375	1752.5	-20.06	42.10	22.04	159.96		
	19975	1712.5	-25.97	42.99	17.02	50.35		
	20175	1732.5	-25.64	42.74	17.10	51.29	V	
	20375	1752.5	-25.18	42.21	17.03	50.47		
			Channel Ba	ndwidth: 5 MHz	/ 16QAM			
X	19975	1712.5	-21.42	42.49	21.07	127.79	1	
	20175	1732.5	-21.28	42.33	21.05	127.26	Н	
	20375	1752.5	-21.05	42.10	21.05	127.35		
	19975	1712.5	-26.87	42.99	16.12	40.93		
	20175	1732.5	-26.68	42.74	16.06	40.36	V	
	20375	1752.5	-26.12	42.21	16.09	40.64		
			Channel Ba	ndwidth: 5 MHz	/ 64QAM			
Х	19975	1712.5	-22.36	42.49	20.13	102.92		
	20175	1732.5	-21.96	42.33	20.37	108.82	Н	
	20375	1752.5	-21.81	42.10	20.29	106.91		
	19975	1712.5	-27.21	42.99	15.78	37.84		
	20175	1732.5	-27.26	42.74	15.48	35.32	V	
	20375	1752.5	-26.95	42.21	15.26	33.57		



	LTE Band 4							
Channel Bandwidth: 10 MHz / QPSK								
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)	
	20000	1715.0	-20.46	42.49	22.03	159.40		
	20175	1732.5	-20.30	42.33	22.03	159.48	Н	
Х	20350	1750.0	-20.04	42.10	22.06	160.69		
^	20000	1715.0	-25.93	42.99	17.06	50.82		
	20175	1732.5	-25.70	42.74	17.04	50.58	V	
	20350	1750.0	-25.16	42.21	17.05	50.70		
		(Channel Bar	ndwidth: 10 MHz	/ 16QAM			
	20000	1715.0	-21.46	42.49	21.03	126.62		
	20175	1732.5	-21.32	42.33	21.01	126.10	Н	
Х	20350	1750.0	-21.07	42.10	21.03	126.77		
^	20000	1715.0	-26.89	42.99	16.10	40.74		
	20175	1732.5	-26.67	42.74	16.07	40.46	V	
	20350	1750.0	-26.13	42.21	16.08	40.55		
		(Channel Bar	ndwidth: 10 MHz	/ 64QAM			
	20000	1715.0	-22.36	42.49	20.13	102.92		
	20175	1732.5	-22.01	42.33	20.32	107.57	Н	
V	20350	1750.0	-21.85	42.10	20.25	105.93		
Х	20000	1715.0	-27.22	42.99	15.77	37.76		
	20175	1732.5	-27.14	42.74	15.60	36.31	V	
	20350	1750.0	-26.85	42.21	15.36	34.36		



	LTE Band 4								
	Channel Bandwidth: 15 MHz / QPSK								
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)		
	20025	1717.5	-20.46	42.49	22.03	159.40			
	20175	1732.5	-20.26	42.33	22.07	160.95	Н		
X	20325	1747.5	-20.04	42.10	22.06	160.69			
^	20025	1717.5	-25.96	42.99	17.03	50.47			
	20175	1732.5	-25.61	42.74	17.13	51.64	V		
	20325	1747.5	-25.20	42.21	17.01	50.23			
		(Channel Bar	ndwidth: 15 MHz	/ 16QAM				
	20025	1717.5	-21.43	42.49	21.06	127.50			
	20175	1732.5	-21.32	42.33	21.01	126.10	Н		
X	20325	1747.5	-21.00	42.10	21.10	128.82			
^	20025	1717.5	-26.93	42.99	16.06	40.36			
	20175	1732.5	-26.74	42.74	16.00	39.81	V		
	20325	1747.5	-26.18	42.21	16.03	40.09			
		(Channel Bar	ndwidth: 15 MHz	/ 64QAM				
	20025	1717.5	-21.96	42.49	20.53	112.85			
	20175	1732.5	-22.12	42.33	20.21	104.88	Н		
	20325	1747.5	-21.88	42.10	20.22	105.20			
X	20025	1717.5	-27.15	42.99	15.84	38.37			
	20175	1732.5	-27.26	42.74	15.48	35.32	V		
	20325	1747.5	-27.03	42.21	15.18	32.95			



	LTE Band 4							
Channel Bandwidth: 20 MHz / QPSK								
Plane	Channel	Frequency (MHz)	LVL (dBm)	Correction Factor (dB)	EIRP (dBm)	EIRP (mW)	Polarization (H/V)	
	20050	1720.0	-20.46	42.49	22.03	159.40		
	20175	1732.5	-20.13	42.33	22.20	165.84	Н	
Х	20300	1745.0	-20.06	42.10	22.04	159.96		
^	20050	1720.0	-25.97	42.99	17.02	50.35		
	20175	1732.5	-25.62	42.74	17.12	51.52	V	
	20300	1745.0	-25.04	42.21	17.17	52.12		
		(Channel Bar	ndwidth: 20 MHz	/ 16QAM			
	20050	1720.0	-21.42	42.49	21.07	127.79		
	20175	1732.5	-21.24	42.33	21.09	128.44	Н	
Х	20300	1745.0	-20.94	42.10	21.16	130.62		
^	20050	1720.0	-26.97	42.99	16.02	39.99		
	20175	1732.5	-26.69	42.74	16.05	40.27	V	
	20300	1745.0	-26.05	42.21	16.16	41.30		
		(Channel Bar	ndwidth: 20 MHz	/ 64QAM			
	20050	1720.0	-22.33	42.49	20.16	103.63		
	20175	1732.5	-21.95	42.33	20.38	109.07	Н	
V	20300	1745.0	-21.54	42.10	20.56	113.76		
Х	20050	1720.0	-27.25	42.99	15.74	37.50		
	20175	1732.5	-27.41	42.74	15.33	34.12	V	
	20300	1745.0	-27.01	42.21	15.20	33.11		



4.2 Frequency Stability Measurement

4.2.1 Limits of Frequency Stability Measurement

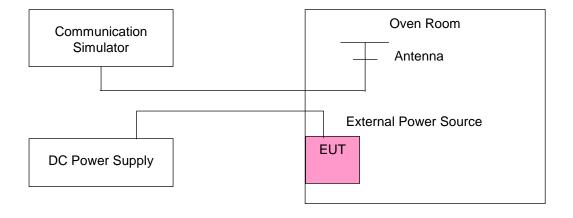
The frequency stability shall be sufficient to ensure that the fundamental emissions stay within the authorized bands of operation.

4.2.2 Test Procedure

- a. Device is placed at the oven room. The oven room could control the temperatures and humidity. Power warm up is at least 15 min and power applied should perform before recording frequency error.
- b. EUT is connected the external power supply to control the DC input power. The test voltage range is from minimum to maximum working voltage. Each step shall be record the frequency error rate.
- c. The temperature range step is 10 degrees in this test items. All temperature levels shall be hold the ± 0.5 $^{\circ}$ C during the measurement testing. The each temperature step shall be at least 0.5 hours, consider the EUT could be test under the stability condition.

Note: The frequency error was recorded frequency error from the communication simulator.

4.2.3 Test Setup





4.2.4 Test Results

Frequency Error vs. Voltage

Voltage	Low Channel		High C	Limit (ppm)	
(Volts)	Frequency (MHz) Frequency Er (ppm)		Frequency (MHz)	Frequency Error (ppm)	(pp)
3.5	1712.400002	0.001	1752.600002	0.001	2.5
3.85	1712.400001	0.001	1752.600001	0.001	2.5
4.3	1712.400002	0.001	1752.600004	0.002	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

Temp. (°C)	Low C	hannel	High C	hannel	Limit (ppm)
· [(0)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
-30	1712.400002	0.001	1752.600004	0.002	2.5
-20	1712.400002	0.001	1752.600001	0.001	2.5
-10	1712.400003	0.002	1752.600001	0.001	2.5
0	1712.400002	0.001	1752.600003	0.002	2.5
10	1712.400003	0.002	1752.600002	0.001	2.5
20	1712.399997	-0.002	1752.599998	-0.001	2.5
30	1712.399996	-0.002	1752.599998	-0.001	2.5
40	1712.399997	-0.002	1752.599998	-0.001	2.5
50	1712.399999	-0.001	1752.599997	-0.002	2.5
55	1712.399996	-0.002	1752.599996	-0.002	2.5



Voltage						
(Volts)	Low C	Low Channel High Channel				
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)		
3.5	1710.700001	0.001	1754.300002	0.001	2.5	
3.85	1710.700001	0.001	1754.300002	0.001	2.5	
4.3	1710.700003	0.002	1754.300003	0.002	2.5	

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 1.4 MHz						
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)			
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	1710.700002	0.001	1754.300004	0.002	2.5			
-20	1710.700003	0.002	1754.300003	0.002	2.5			
-10	1710.700002	0.001	1754.300003	0.002	2.5			
0	1710.700004	0.002	1754.300002	0.001	2.5			
10	1710.700003	0.002	1754.300004	0.002	2.5			
20	1710.699998	-0.001	1754.299999	-0.001	2.5			
30	1710.699999	-0.001	1754.299998	-0.001	2.5			
40	1710.699999	-0.001	1754.299997	-0.001	2.5			
50	1710.699999	-0.001	1754.299997	-0.002	2.5			
55	1710.699998	-0.001	1754.299997	-0.002	2.5			



Voltage					
(Volts)	Low C	Low Channel High Channel			
	Frequency (MHz)	Frequency Error (ppm)			
3.5	1711.500003	0.002	1753.500004	0.002	2.5
3.85	1711.500002	0.001	1753.500002	0.001	2.5
4.3	1711.500004	0.002	1753.500002	0.001	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 3 MHz						
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)			
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	1711.500003	0.002	1753.500004	0.002	2.5			
-20	1711.500001	0.001	1753.500004	0.002	2.5			
-10	1711.500003	0.002	1753.500002	0.001	2.5			
0	1711.500004	0.002	1753.500002	0.001	2.5			
10	1711.500001	0.001	1753.500003	0.002	2.5			
20	1711.499999	-0.001	1753.499996	-0.002	2.5			
30	1711.499996	-0.002	1753.499997	-0.002	2.5			
40	1711.499998	-0.001	1753.499999	-0.001	2.5			
50	1711.499999	-0.001	1753.499997	-0.002	2.5			
55	1711.499997	-0.002	1753.499999	-0.001	2.5			



Voltage					
(Volts)	Low Channel High Channel				Limit (ppm)
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	1712.500003	0.002	1752.500001	0.001	2.5
3.85	1712.500004	0.002	1752.500004	0.002	2.5
4.3	1712.500004	0.002	1752.500002	0.001	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 5 MHz						
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)			
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	1712.500004	0.002	1752.500004	0.002	2.5			
-20	1712.500002	0.001	1752.500001	0.001	2.5			
-10	1712.500003	0.002	1752.500003	0.002	2.5			
0	1712.500001	0.001	1752.500002	0.001	2.5			
10	1712.500004	0.002	1752.500001	0.001	2.5			
20	1712.499997	-0.002	1752.499997	-0.002	2.5			
30	1712.499999	-0.001	1752.499998	-0.001	2.5			
40	1712.499997	-0.002	1752.499999	-0.001	2.5			
50	1712.499999	-0.001	1752.499998	-0.001	2.5			
55	1712.499999	-0.001	1752.499999	-0.001	2.5			



Voltage						
(Volts)	Low C	Low Channel High Channel				
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)		
3.5	1715.000004	0.002	1750.000004	0.002	2.5	
3.85	1715.000003	0.001	1750.000002	0.001	2.5	
4.3	1715.000003	0.001	1750.000002	0.001	2.5	

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 10 MHz						
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)			
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	1715.000002	0.001	1750.000002	0.001	2.5			
-20	1715.000002	0.001	1750.000002	0.001	2.5			
-10	1715.000004	0.002	1750.000004	0.002	2.5			
0	1715.000002	0.001	1750.000001	0.001	2.5			
10	1715.000004	0.002	1750.000004	0.002	2.5			
20	1714.999999	-0.001	1749.999997	-0.001	2.5			
30	1714.999999	-0.001	1749.999997	-0.002	2.5			
40	1714.999997	-0.002	1749.999998	-0.001	2.5			
50	1714.999996	-0.002	1749.999996	-0.002	2.5			
55	1714.999997	-0.002	1749.999996	-0.002	2.5			



Voltage					
(Volts)	Low Channel		High Channel		Limit (ppm)
(2 .2,	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	1717.500002	0.001	1747.500002	0.001	2.5
3.85	1717.500003	0.002	1747.500004	0.002	2.5
4.3	1717.500003	0.002	1747.500004	0.002	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
-30	1717.500003	0.002	1747.500004	0.002	2.5
-20	1717.500003	0.002	1747.500002	0.001	2.5
-10	1717.500003	0.002	1747.500002	0.001	2.5
0	1717.500002	0.001	1747.500004	0.002	2.5
10	1717.500002	0.001	1747.500003	0.002	2.5
20	1717.499999	-0.001	1747.499999	-0.001	2.5
30	1717.499997	-0.002	1747.499998	-0.001	2.5
40	1717.499998	-0.001	1747.499998	-0.001	2.5
50	1717.499998	-0.001	1747.499997	-0.002	2.5
55	1717.499997	-0.002	1747.499997	-0.002	2.5



Voltage		Channel Bandwidth: 20 MHz					
(Volts)	Law Ohannal		hannel	Limit (ppm)			
(12.112)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)			
3.5	1720.000003	0.002	1745.000003	0.001	2.5		
3.85	1720.000001	0.001	1745.000002	0.001	2.5		
4.3	1720.000003	0.002	1745.000002	0.001	2.5		

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 20 MHz						
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)			
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	1720.000002	0.001	1745.000002	0.001	2.5			
-20	1720.000003	0.002	1745.000003	0.002	2.5			
-10	1720.000003	0.001	1745.000004	0.002	2.5			
0	1720.000004	0.002	1745.000002	0.001	2.5			
10	1720.000003	0.002	1745.000002	0.001	2.5			
20	1719.999997	-0.002	1744.999998	-0.001	2.5			
30	1719.999999	-0.001	1744.999997	-0.002	2.5			
40	1719.999998	-0.001	1744.999997	-0.002	2.5			
50	1719.999996	-0.002	1744.999996	-0.002	2.5			
55	1719.999996	-0.002	1744.999999	-0.001	2.5			



Voltage					
_		hannel H		hannel	Limit (ppm)
(12332)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	699.700003	0.004	715.300001	0.002	2.5
3.85	699.700003	0.004	715.300002	0.003	2.5
4.3	699.700002	0.003	715.300002	0.003	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 1.4 MHz						
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)			
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	699.700004	0.005	715.300002	0.002	2.5			
-20	699.700002	0.002	715.300004	0.005	2.5			
-10	699.700003	0.004	715.300003	0.004	2.5			
0	699.700004	0.005	715.300003	0.004	2.5			
10	699.700003	0.004	715.300002	0.002	2.5			
20	699.699996	-0.006	715.299999	-0.002	2.5			
30	699.699998	-0.003	715.299999	-0.002	2.5			
40	699.699998	-0.003	715.299998	-0.003	2.5			
50	699.699997	-0.005	715.299998	-0.003	2.5			
55	699.699997	-0.004	715.299998	-0.003	2.5			



Voltage					
(Volts) Low Char		hannel	High C	hannel	Limit (ppm)
(:05)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	700.500002	0.002	714.500002	0.002	2.5
3.85	700.500002	0.003	714.500003	0.004	2.5
4.3	700.500001	0.002	714.500003	0.004	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
-30	700.500002	0.003	714.500002	0.002	2.5
-20	700.500003	0.004	714.500001	0.001	2.5
-10	700.500004	0.006	714.500004	0.005	2.5
0	700.500002	0.003	714.500003	0.004	2.5
10	700.500003	0.004	714.500004	0.006	2.5
20	700.499997	-0.004	714.499997	-0.004	2.5
30	700.499998	-0.003	714.499997	-0.004	2.5
40	700.499997	-0.005	714.499999	-0.002	2.5
50	700.499997	-0.005	714.499998	-0.003	2.5
55	700.499997	-0.004	714.499999	-0.002	2.5



Voltage					
(Volts)	I a Ob ann		High Channel		Limit (ppm)
(12332)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	701.500001	0.002	713.500004	0.005	2.5
3.85	701.500003	0.005	713.500003	0.004	2.5
4.3	701.500003	0.005	713.500001	0.002	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

	·						
		Channel Bandwidth: 5 MHz					
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)		
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)			
-30	701.500003	0.005	713.500003	0.004	2.5		
-20	701.500004	0.005	713.500003	0.005	2.5		
-10	701.500003	0.004	713.500004	0.005	2.5		
0	701.500002	0.003	713.500003	0.004	2.5		
10	701.500003	0.004	713.500003	0.003	2.5		
20	701.499996	-0.006	713.499998	-0.002	2.5		
30	701.499996	-0.006	713.499998	-0.002	2.5		
40	701.499997	-0.004	713.499999	-0.002	2.5		
50	701.499998	-0.004	713.499998	-0.003	2.5		
55	701.499997	-0.005	713.499998	-0.003	2.5		



Voltage					
(Volts)	Low Channel		High Channel		Limit (ppm)
(12.112)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	704.000004	0.005	711.000004	0.005	2.5
3.85	704.000003	0.004	711.000002	0.003	2.5
4.3	704.000001	0.001	711.000004	0.005	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 10 MHz								
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)					
	Frequency (MHz)	quency (MHz) Frequency Error (ppm)		Frequency Error (ppm)						
-30	704.000001	0.002	711.000002	0.002	2.5					
-20	704.000002	0.002	711.000002	0.003	2.5					
-10	704.000004	0.005	711.000001	0.002	2.5					
0	704.000003	0.005	711.000004	0.005	2.5					
10	704.000004	0.005	711.000002	0.003	2.5					
20	703.999997	-0.005	710.999998	-0.003	2.5					
30	703.999998	-0.003	710.999998	-0.003	2.5					
40	703.999998	-0.003	710.999998	-0.004	2.5					
50	703.999996	-0.006	710.999999	-0.002	2.5					
55	703.999997	-0.004	710.999998	-0.002	2.5					



Voltage		Channel Bandwidth: 5 MHz								
(Volts)	Low C	Limit (ppm)								
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)						
3.5	779.500002	0.003	784.500002	0.003	2.5					
3.85	779.500002	0.002	784.500003	0.003	2.5					
4.3	779.500004	0.005	784.500004	0.005	2.5					

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Band	dwidth: 5 MHz		
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)
	Frequency (MHz) Frequency Error (ppm)		Frequency (MHz)	equency (MHz) Frequency Error (ppm)	
-30	779.500001	0.002	784.500003	0.004	2.5
-20	779.500004	0.005	784.500001	0.001	2.5
-10	779.500003	0.003	784.500003	0.003	2.5
0	779.500003	0.004	784.500004	0.005	2.5
10	779.500002	0.002	784.500003	0.004	2.5
20	779.499998	-0.002	784.499997	-0.004	2.5
30	779.499998	-0.002	784.499996	-0.005	2.5
40	779.499997	-0.004	784.499998	-0.002	2.5
50	779.499997	-0.004	784.499998	-0.003	2.5
55	779.499997	-0.004	784.499999	-0.002	2.5



	LTE B		
Voltage (Volts)	Channel Band	Limit (ppm)	
(Voits)	Frequency (MHz)	Frequency Error (ppm)	
3.5	782.000004	0.004	2.5
3.85	782.000003	0.003	2.5
4.3	782.000002	0.002	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

	LTE B		
Temp. (℃)	Channel Band	Limit (ppm)	
	Frequency (MHz)	Frequency Error (ppm)	
-30	782.000004	0.005	2.5
-20	782.000002	0.002	2.5
-10	782.000003	0.004	2.5
0	782.000002	0.003	2.5
10	782.000003	0.003	2.5
20	781.999997	-0.004	2.5
30	781.999998	-0.002	2.5
40	781.999996	-0.005	2.5
50	781.999998	-0.002	2.5
55	781.999999	-0.001	2.5



Voltage					
(Volts)	Low Channel High Channel				Limit (ppm)
(10.10)	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	706.500004	0.005	713.500002	0.003	2.5
3.85	706.500003	0.005	713.500003	0.004	2.5
4.3	706.500002	0.003	713.500003	0.004	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

		Channel Bandwidth: 5 MHz								
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)					
	Frequency (MHz) Frequency Error (ppm)		Frequency (MHz) Frequency Error (ppm)							
-30	706.500002	0.003	713.500003	0.004	2.5					
-20	706.500004	0.005	713.500002	0.003	2.5					
-10	706.500002	706.500002 0.003		0.002	2.5					
0	706.500002	0.002	713.500002	0.003	2.5					
10	706.500003	0.005	713.500004	0.005	2.5					
20	706.499998	-0.003	713.499998	-0.004	2.5					
30	706.499997	-0.005	713.499999	-0.002	2.5					
40	706.499996	706.499996 -0.005		-0.003	2.5					
50	706.499997	-0.004	713.499996	-0.006	2.5					
55	706.499998	-0.003	713.499996	-0.005	2.5					



Voltage					
(Volts)	Low C	hannel	High C	hannel	Limit (ppm)
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.5	709.000003	0.004	711.000002	0.003	2.5
3.85	709.000004	0.006	711.000003 0.004		2.5
4.3	709.000003	0.004	711.000002	0.002	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.5 Vdc to 4.3 Vdc.

	·									
		Channel Bandwidth: 10 MHz								
Temp. (℃)	Low C	hannel	High C	hannel	Limit (ppm)					
	Frequency (MHz) Frequency Error (ppm) F		Frequency (MHz)	uency (MHz) Frequency Error (ppm)						
-30	709.000002	0.003	711.000004	0.005	2.5					
-20	709.000002	0.002	711.000001	0.002	2.5					
-10	709.000001	709.000001 0.002		0.002	2.5					
0	709.000001	0.002	711.000003	0.005	2.5					
10	709.000003	0.005	711.000001	0.002	2.5					
20	708.999998	-0.003	710.999996	-0.006	2.5					
30	708.999996	-0.006	710.999998	-0.002	2.5					
40	708.999997	-0.004	710.999999	-0.002	2.5					
50	708.999998	-0.004	710.999999	-0.001	2.5					
55	708.999997	-0.004	710.999999	-0.002	2.5					



4.3 Occupied Bandwidth Measurement

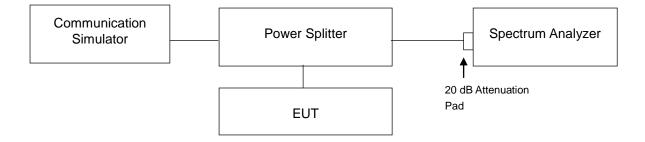
4.3.1 Limits of Occupied Bandwidth Measurement

The width of a frequency band such that, below the lower and above the upper frequency limits, the mean powers emitted are each equal to a specified percentage 0.5 % of the total mean power of a given emission.

4.3.2 Test Procedure

- a. The conducted occupied bandwidth used the power splitter via EUT RF power connector between simulation base station and spectrum analyzer.
- b. Use OBW measurement function of Spectrum analyzer to measure 99 % occupied bandwidth.

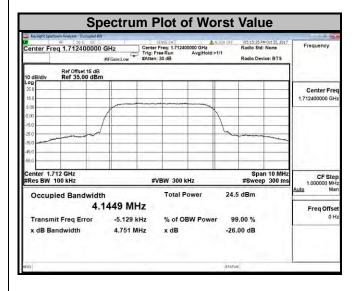
4.3.3 Test Setup





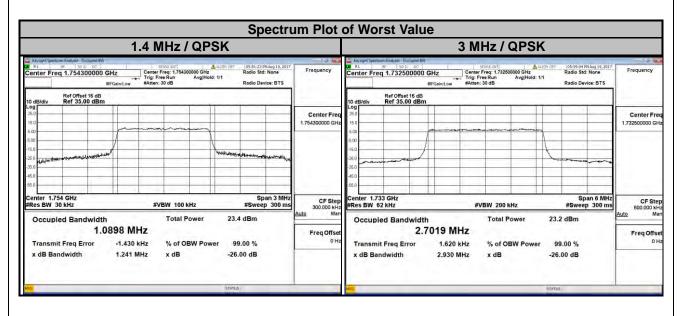
4.3.4 Test Result

WCDMA								
Channel	Frequency (MHz)	99 % Occupied Bandwidth (MHz)						
1312	1712.4	4.1449						
1413	1732.6	4.1350						
1513	1752.6	4.1348						



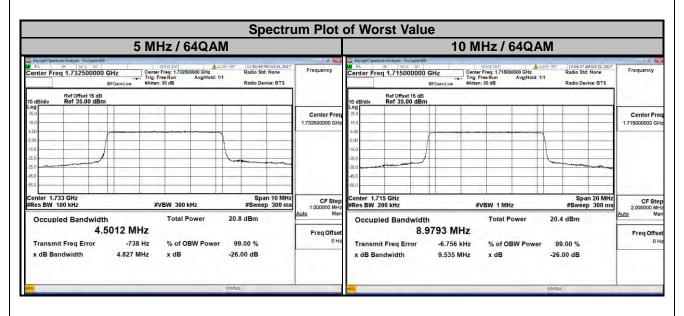


	LTE Band 4												
Channel Bandwidth: 1.4 MHz					(Channel Band	dwidth: 3	MHz					
Channel	Frequency		99 % Occupie Bandwidth (MF		Channel	Frequency		99 % Occupied Bandwidth (MHz					
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM				
19957	1710.7	1.0860	1.0879	1.0881	19965	1711.5	2.7005	2.6965	2.6979				
20175	1732.5	1.0875	1.0864	1.0890	20175	1732.5	2.7019	2.6989	2.6976				
20393	1754.3	1.0898	1.0890	1.0892	20385	1753.5	2.7007	2.6999	2.6974				



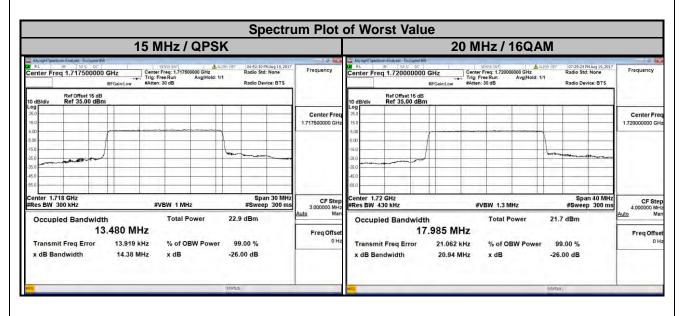


	LTE Band 4												
Channel Bandwidth: 5 MHz					C	hannel Band	width: 1	0 MHz					
Channel	Frequency		% Occup dwidth (I		Channel	Frequency		99 % Occupied Bandwidth (MHz)					
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM				
19975	1712.5	4.4882	4.4862	4.4966	20000	1715.0	8.9736	8.9719	8.9793				
20175	1732.5	4.4903	4.4944	4.5012	20175	1732.5	8.9704	8.9717	8.9721				
20375	1752.5	4.4905	4.4913	4.5010	20350	1750.0	8.9726	8.9788	8.9760				



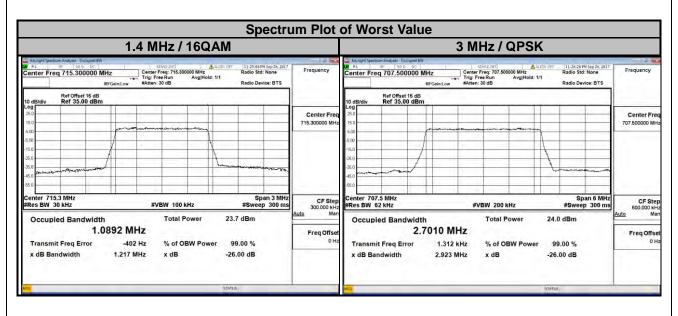


LTE Band 4											
C	Channel Band	5 MHz		Channel Bandwidth: 20 MHz							
Channel	Frequency		% Occup dwidth (N		Channel	Frequency	99 % Occupied Bandwidth (MHz)				
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	PSK 16QAM	64QAM		
20025	1717.5	13.480	13.474	13.458	20050	1720.0	17.960	17.985	17.950		
20175	1732.5	13.466	13.450	13.439	20175	1732.5	17.929	17.947	17.931		
20325	1747.5	13.477	13.466	13.451	20300	1745.0	17.962	17.983	17.954		



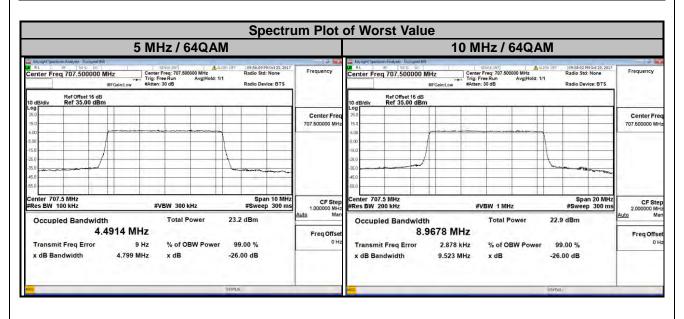


LTE Band 12										
С	hannel Band	(Channel Bandwidth: 3 MHz							
Channel	Frequency		99 % Occupied Bandwidth (MHz)		Channel	Frequency	99 % Occupied Bandwidth (MHz)			
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM	
23017	699.7	1.0864	1.0872	1.0858	23025	700.5	2.7002	2.6977	2.7024	
23095	707.5	1.0865	1.0855	1.0869	23095	707.5	2.7010	2.6966	2.7008	
23173	715.3	1.0864	1.0892	1.0872	23165	714.5	2.6984	2.6954	2.7008	



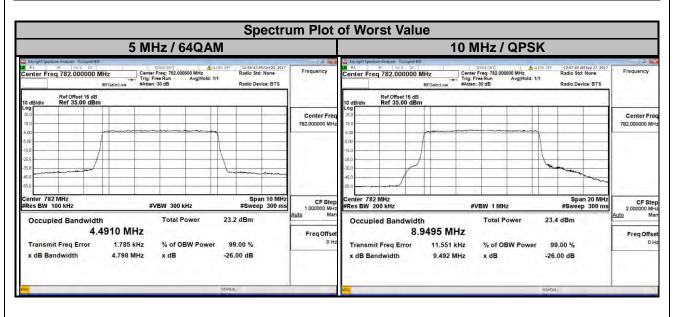


LTE Band 12											
(Channel Band	Channel Bandwidth: 10 MHz									
Channel	Frequency	99 % Occupied Bandwidth (MHz)		Channel	Frequency	99 % Occupied Bandwidth (MHz)					
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM		
23035	701.5	4.4884	4.4913	4.4888	23060	704.0	8.9626	8.9643	8.9567		
23095	707.5	4.4889	4.4893	4.4914	23095	707.5	8.9641	8.9671	8.9678		
23155	713.5	4.4830	4.4874	4.4854	23130	711.0	8.9582	8.9638	8.9564		



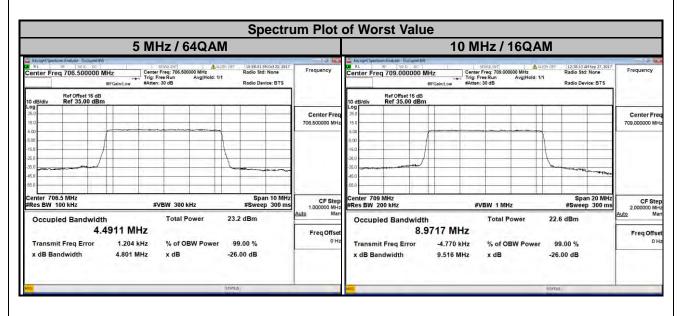


LTE Band 13											
(Channel Band	Channel Bandwidth: 10 MHz									
Channel	Frequency	99 % Occupied Bandwidth (MHz)			Channel	Frequency	99 % Occupied Bandwidth (MHz)				
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK 1	16QAM	64QAM		
23205	779.5	4.4826	4.4816	4.4861		782.0	8.9495	8.9476	8.9450		
23230	782.0	4.4835	4.4845	4.4910	23230						
23255	784.5	4.4885	4.4896	4.4891							





LTE Band 17											
(Channel Band	dwidth: 5	MHz	Channel Bandwidth: 10 MHz							
Channel	Frequency	99 % Occupied Bandwidth (MHz)			Channel	Frequency	99 % Occupied Bandwidth (MHz)				
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM		
23755	706.5	4.4881	4.4881	4.4911	23780	709.0	8.9697	8.9717	8.9644		
23790	710.0	4.4882	4.4900	4.4877	23790	710.0	8.9642	8.9647	8.9649		
23825	713.5	4.4840	4.4834	4.4853	23800	711.0	8.9591	8.9616	8.9558		





4.4 Band Edge Measurement

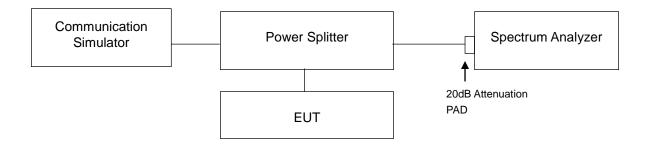
4.4.1 Limits of Band Edge Measurement

For operations in the 698-787 MHz band, the power of any emission outside a licensee's frequency band(s) of operation shall be attenuated below the transmitter power (P) within the licensed band(s) of operation, measured in watts, by at least 43 + 10 log (P) dB. Compliance with this provision is based on the use of measurement instrumentation employing a resolution bandwidth of 100 kilohertz or greater.

However, in the 100 kilohertz bands immediately outside and adjacent to a licensee's frequency block, a resolution bandwidth of at least 30 kHz may be employed.

For operations in the 1710–1755 MHz bands, the power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) by at least 43 + 10 log10(P) dB.

4.4.2 Test Setup

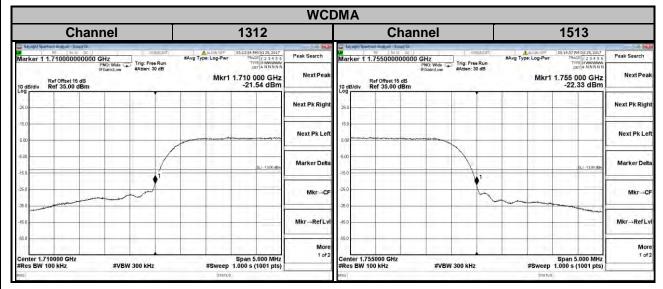


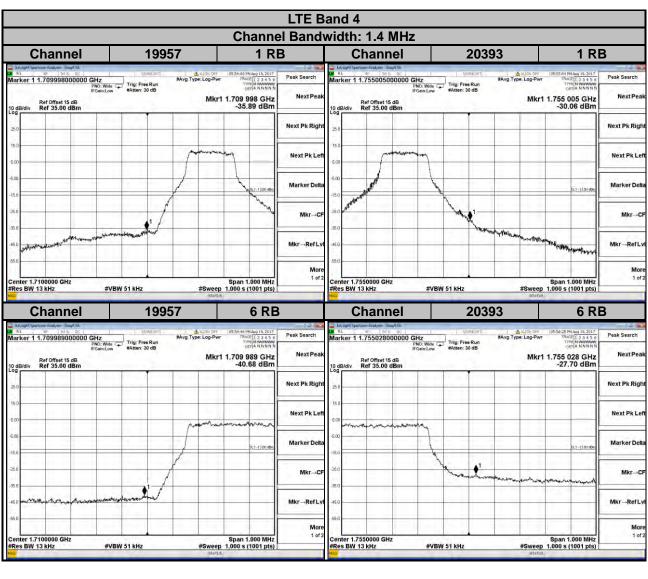
4.4.3 Test Procedures

- a. All measurements were done at low and high operational frequency range.
- b. The center frequency of spectrum is the band edge frequency and span is 5 MHz. RB of the spectrum is 100 kHz and VB of the spectrum is 300 kHz (WCDMA).
- c. The center frequency of spectrum is the band edge frequency and span is 1 MHz. RB of the spectrum is 13 kHz and VB of the spectrum is 51 kHz (LTE Bandwidth 1.4 MHz).
- d. The center frequency of spectrum is the band edge frequency and span is 1 MHz. RB of the spectrum is 30 kHz and VB of the spectrum is 100 kHz (LTE Bandwidth 3 MHz).
- e. The center frequency of spectrum is the band edge frequency and span is 1 MHz. RB of the spectrum is 100 kHz and VB of the spectrum is 300 kHz (LTE Bandwidth 5 MHz/10 MHz).
- f. The center frequency of spectrum is the band edge frequency and span is 1 MHz. RB of the spectrum is 150 kHz and VB of the spectrum is 470 kHz (LTE Bandwidth 15 MHz).
- g. The center frequency of spectrum is the band edge frequency and span is 1 MHz. RB of the spectrum is 180 kHz and VB of the spectrum is 560 kHz (LTE Bandwidth 20 MHz).
- h. Record the max. trace plot into the test report.

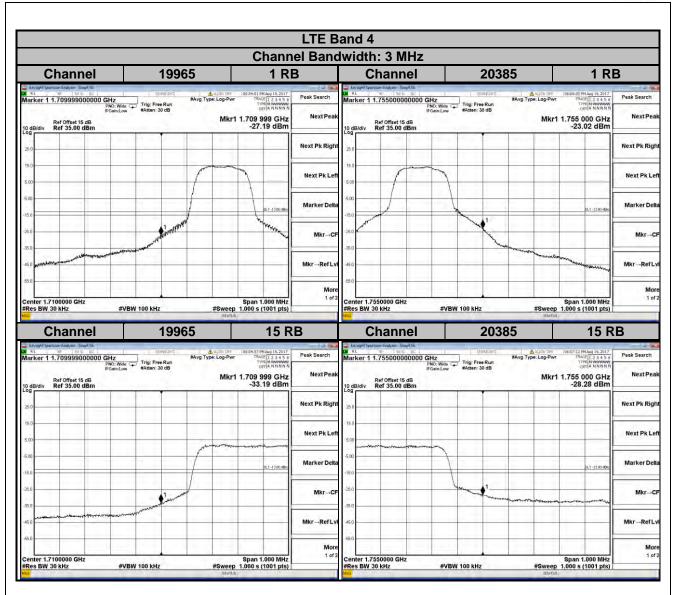


4.4.4 Test Results

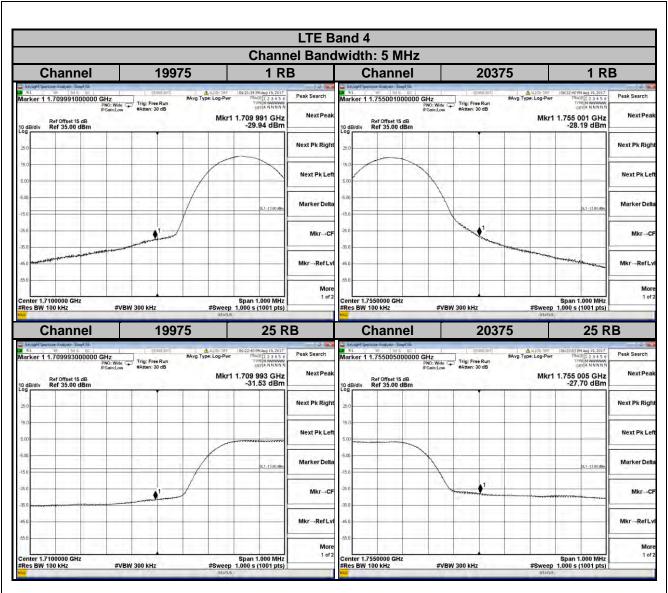




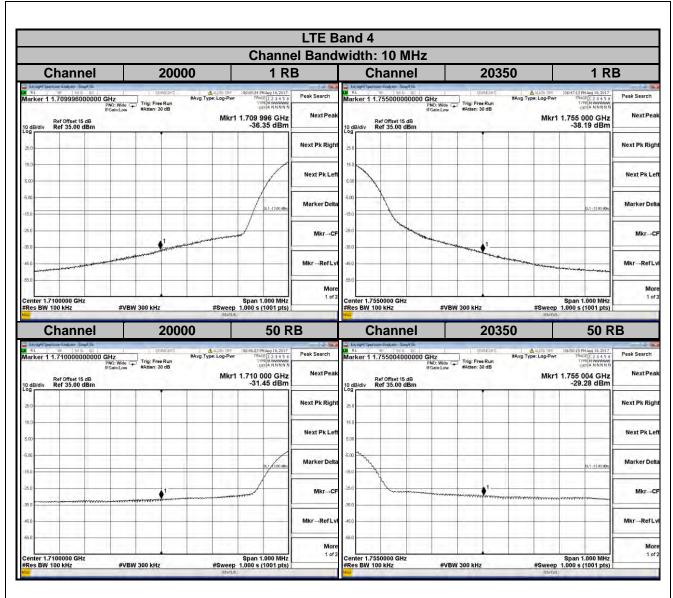




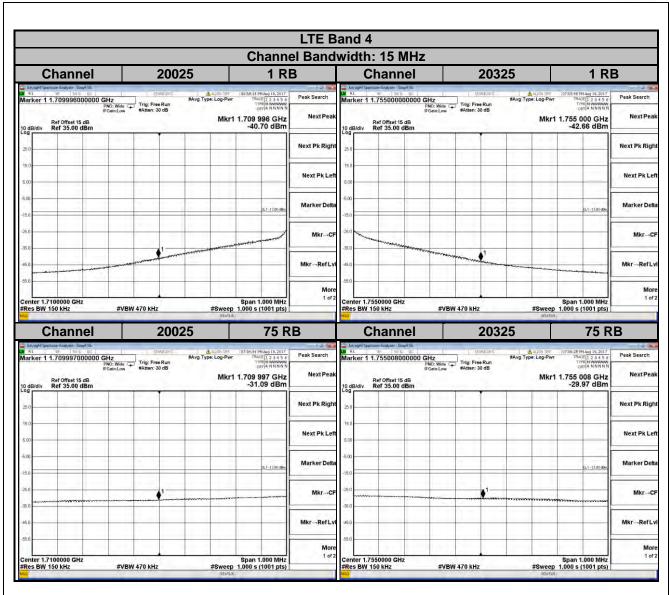




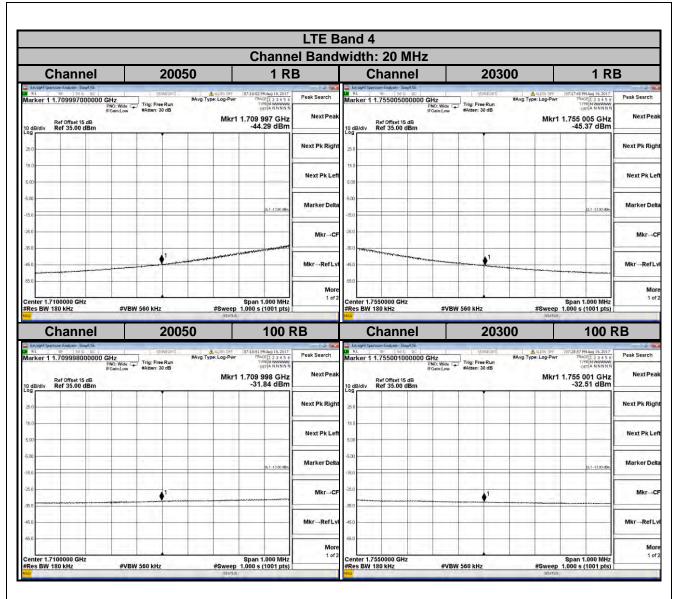




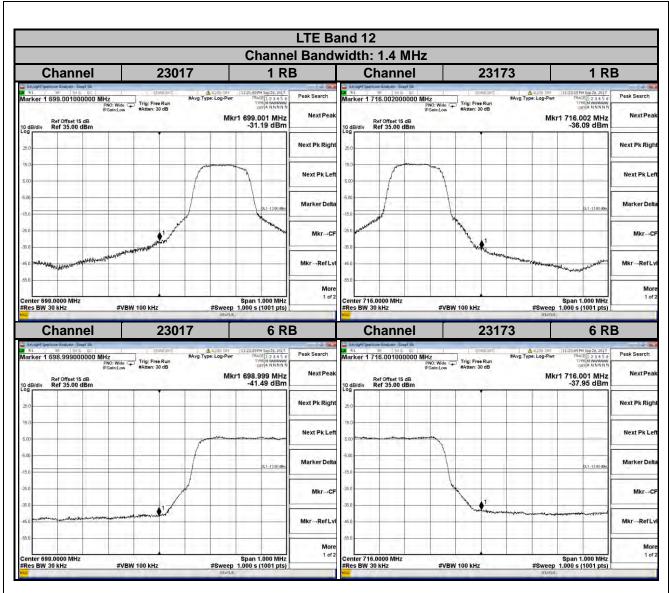




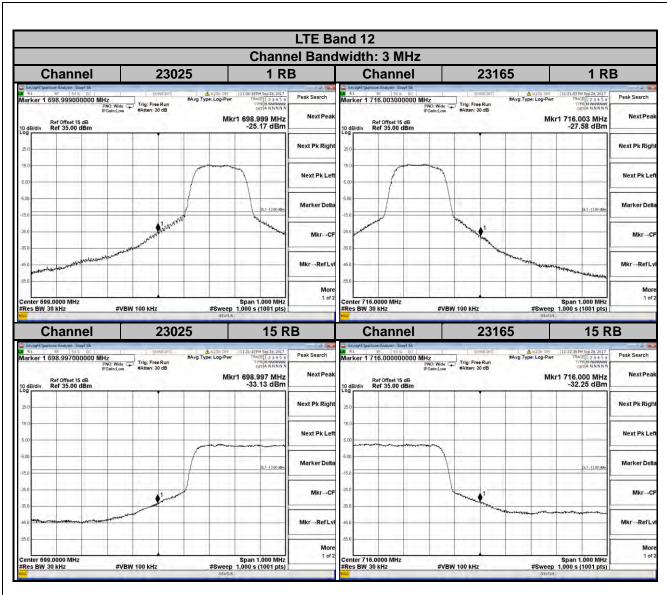




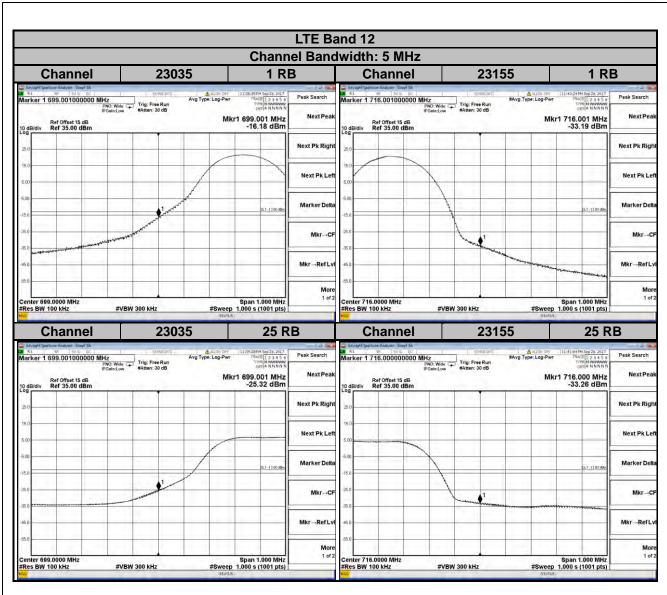




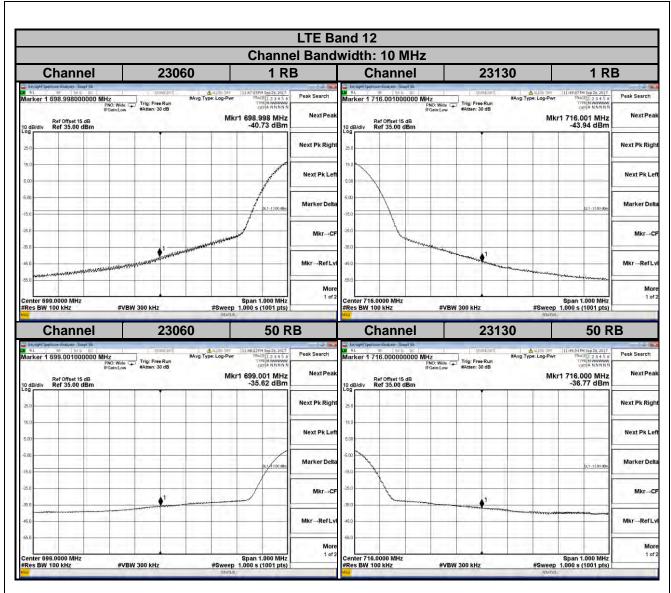




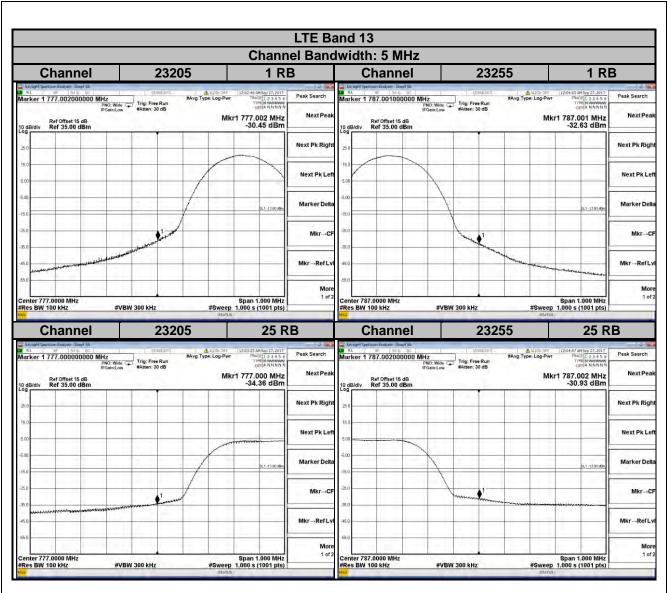




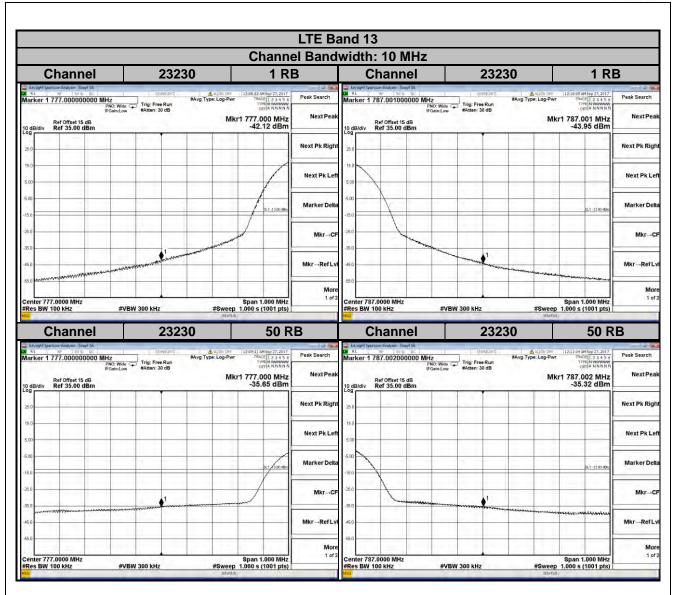




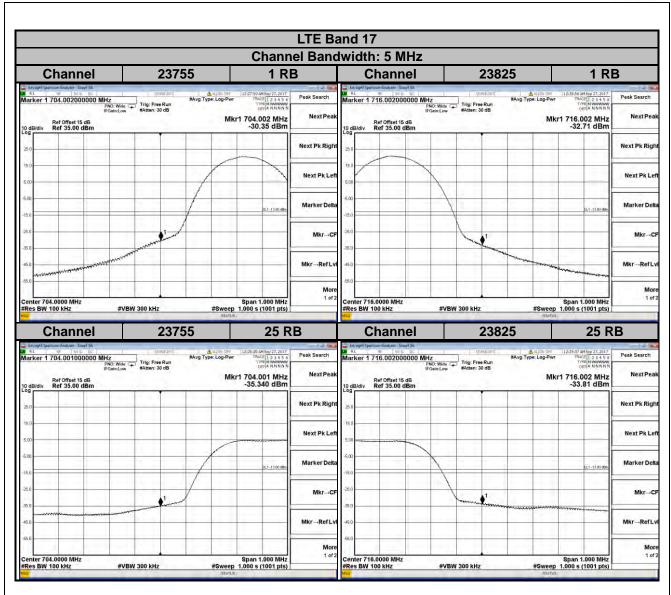




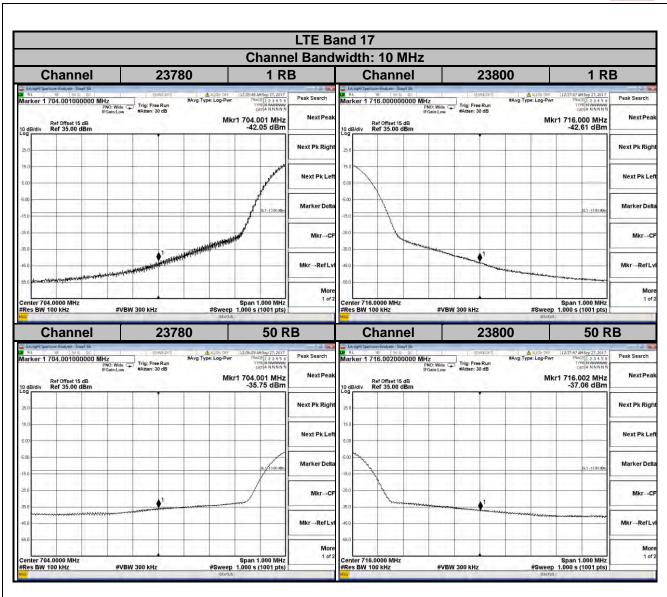




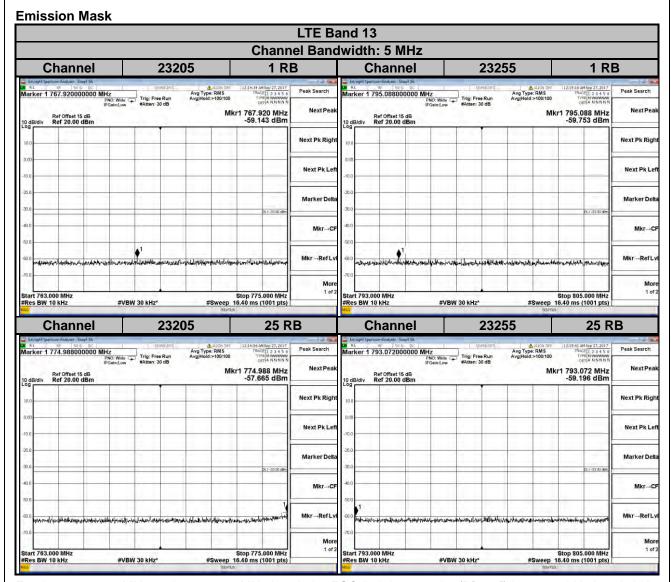










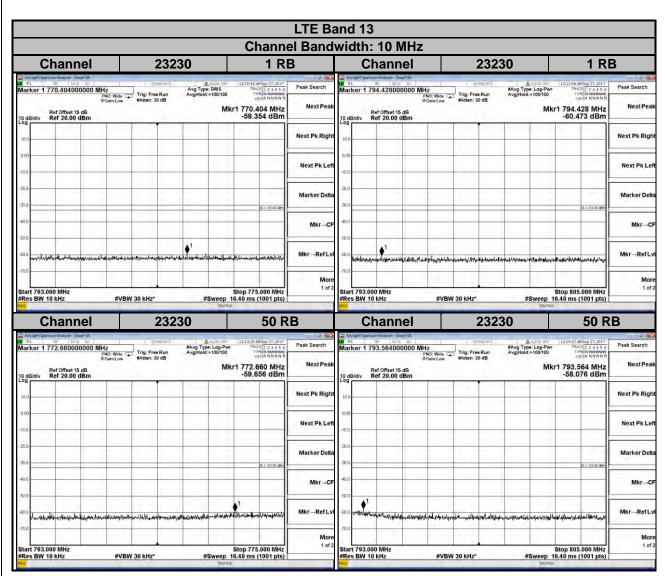


For the 763 - 775 MHz and 793 - 805 MHz band, the FCC limit is 65+10log(P[watt]) in a 6.25 kHz bandwidth. Since it was not possible to set the resolution bandwidth to 6.25 kHz with the available equipment, a bandwidth of 10 kHz was used instead to show compliance. By using a 10 kHz bandwidth on the spectrum analyzer.

 $10\log(10kHz/6.25kHz) = 2.04 dB$

Limit line = -35 dBm + 2.04 dB = -32.96 dBm





For the 763 - 775 MHz and 793 - 805 MHz band, the FCC limit is 65+10log(P[watt]) in a 6.25 kHz bandwidth. Since it was not possible to set the resolution bandwidth to 6.25 kHz with the available equipment, a bandwidth of 10 kHz was used instead to show compliance. By using a 10 kHz bandwidth on the spectrum analyzer.

 $10\log(10kHz/6.25kHz) = 2.04 dB$

Limit line = -35 dBm + 2.04 dB =-32.96 dBm

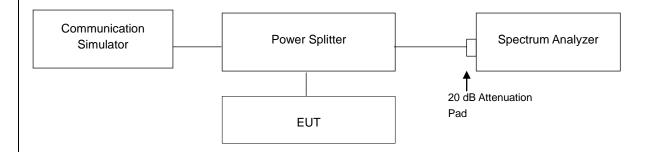


4.5 Peak to Average Ratio

4.5.1 Limits of Peak to Average Ratio Measurement

In measuring transmissions in this band using an average power technique, the peak to-average ratio (PAR) of the transmission may not exceed 13 dB.

4.5.2 Test Setup



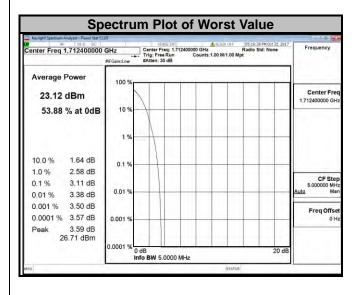
4.5.3 Test Procedures

- 1. Set resolution/measurement bandwidth ≥ signal's occupied bandwidth;
- 2. Set the number of counts to a value that stabilizes the measured CCDF curve;
- 3. Record the maximum PAPR level associated with a probability of 0.1 %.



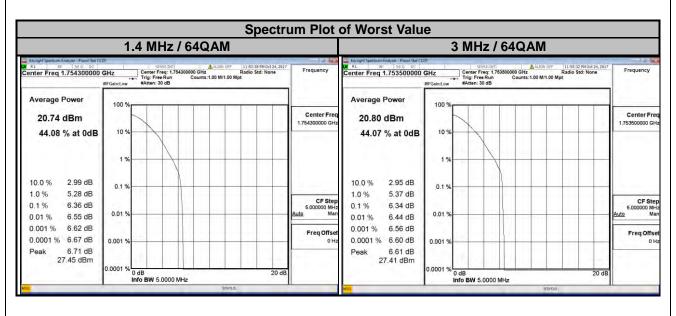
4.5.4 Test Results

WCDMA										
Channel	Frequency (MHz)	Peak to Average Ratio (dB)								
1312	1712.4	3.11								
1413	1732.6	3.05								
1513	1752.6	3.04								



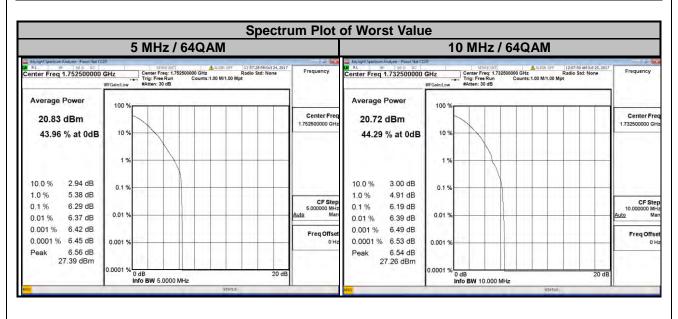


	LTE Band 4														
Channel Bandwidth: 1.4 MHz						Channel Band	dwidth: 3	MHz							
I (.nannol · · ·	Frequency	Peak to	o Averag (dB)	e Ratio	Channel	Channel Frequency (MHz)	Peak to Average Ratio (dB)								
	(MHz)	QPSK	16QAM	64QAM			QPSK	16QAM	64QAM						
19957	1710.7	4.71	5.49	5.32	19965	1711.5	4.53	5.24	5.35						
20175	1732.5	3.60	4.43	6.35	20175	1732.5	3.63	4.49	6.29						
20393	1754.3	4.67	5.35	6.36	20385	1753.5	4.48	5.23	6.34						



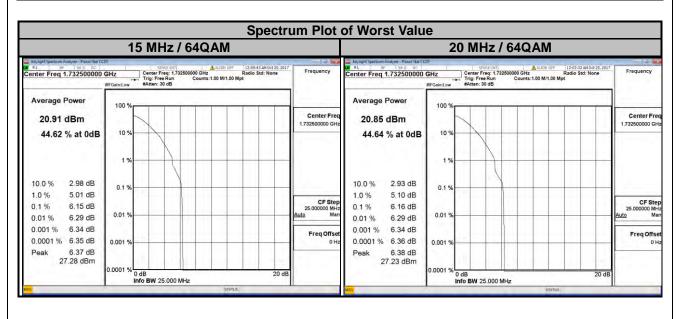


	LTE Band 4														
(Channel Band	C	hannel Band	width: 1	0 MHz										
Channel	Frequency	· (45)		e Ratio	Channel	Frequency	Peak to	o Averag (dB)	e Ratio						
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM						
19975	1712.5	4.53	5.26	5.29	20000	1715.0	4.47	5.23	5.40						
20175	1732.5	3.86	4.78	6.28	20175	1732.5	4.38	5.15	6.19						
20375	1752.5	3.93	4.67	6.29	20350	1750.0	4.50	5.20	5.67						



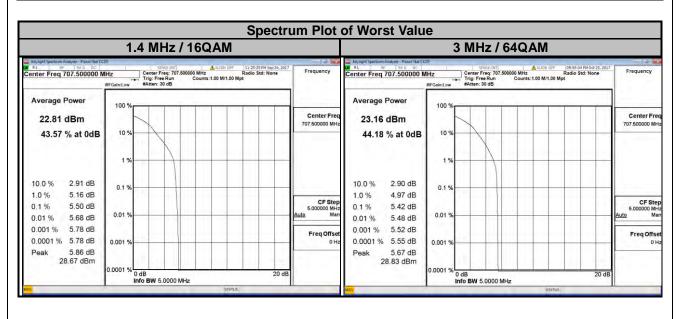


	LTE Band 4														
C	hannel Band	C	hannel Band	width: 2	0 MHz										
Channel	Frequency Peak to Ave		o Averag (dB)	e Ratio	Channel	Frequency	Peak to	Average (dB)	e Ratio						
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM						
20025	1717.5	4.49	5.15	5.20	20050	1720.0	4.45	5.22	5.26						
20175	1732.5	4.39	5.10	6.15	20175	1732.5	4.37	5.08	6.16						
20325	1747.5	4.48	5.21	5.30	20300	1745.0	4.43	5.15	5.90						



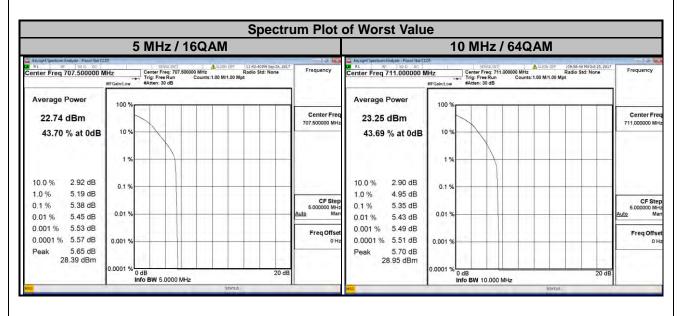


	LTE Band 12														
Channel Bandwidth: 1.4 MHz					(Channel Band	dwidth: 3	MHz							
Channel	Frequency	(42)		Channel	Frequency (MHz)	Peak to Average Ratio (dB)									
	(MHz)	QPSK	16QAM	64QAM		(IVITIZ)	QPSK	16QAM	64QAM						
23017	699.7	3.80	4.52	4.53	23025	700.5	3.74	4.49	4.43						
23095	707.5	4.74	5.50	5.49	23095	707.5	4.56	5.38	5.42						
23173	715.3	4.58	5.42	5.17	23165	714.5	4.28	4.22	5.38						



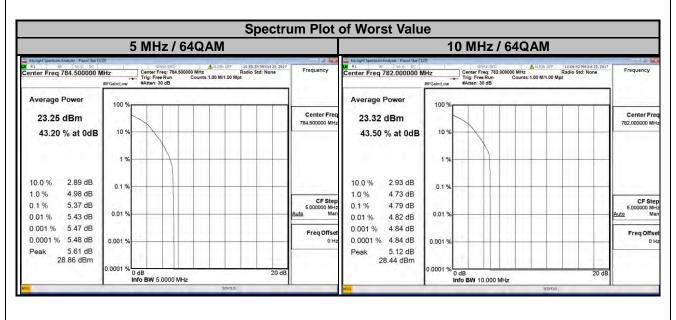


	LTE Band 12														
Channel Bandwidth: 5 MHz					C	hannel Band	width: 1	0 MHz							
Channel	nel Frequency		o Averag (dB)	e Ratio	Channel	Frequency	Peak to Average Ratio (dB)								
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM						
23035	701.5	3.66	4.44	5.35	23060	704.0	3.73	4.52	4.39						
23095	707.5	4.54	5.38	5.34	23095	707.5	4.49	4.27	5.31						
23155	713.5	3.56	4.37	4.38	23130	711.0	4.52	5.23	5.35						



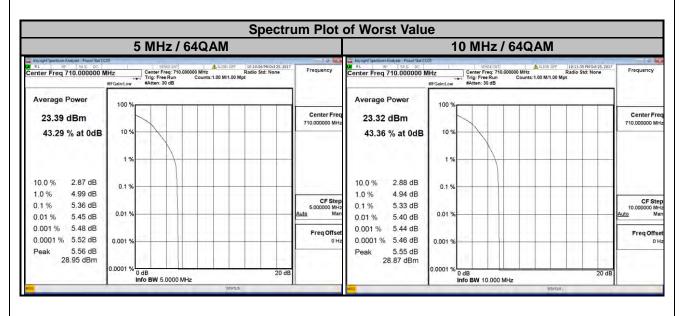


	LTE Band 13														
(Channel Band	C	hannel Band	width: 1	0 MHz										
Channel	Frequency	Peak to	Averag	e Ratio	Channel	Frequency (MHz)	Peak to Average Ratio (dB)								
	(MHz)	QPSK	16QAM	64QAM			QPSK	16QAM	64QAM						
23205	779.5	3.65	4.39	4.58											
23230	782.0	4.56	5.30	5.30	23230	782.0	3.94	4.68	4.79						
23255	784.5	4.55	5.34	5.37											





	LTE Band 17														
(Channel Band	C	hannel Band	width: 1	0 MHz										
Channel	Frequency Peak to Average Ratio (dB)		e Ratio	Channel	Frequency	Peak to Average Ratio (dB)									
	(MHz)	QPSK	16QAM	64QAM		(MHz)	QPSK	16QAM	64QAM						
23755	706.5	4.59	5.26	5.35	23780	709.0	4.49	5.23	5.30						
23790	710.0	4.60	5.29	5.36	23790	710.0	4.52	5.25	5.33						
23825	713.5	4.60	4.25	5.31	23800	711.0	4.51	5.24	5.31						



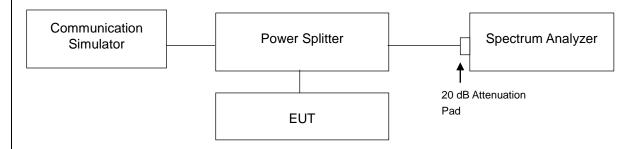


4.6 Conducted Spurious Emissions

4.6.1 Limits of Conducted Spurious Emissions Measurement

The power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) by at least 43 +10 log10(P) dB. The limit of emission is equal to -13 dBm.

4.6.2 Test Setup

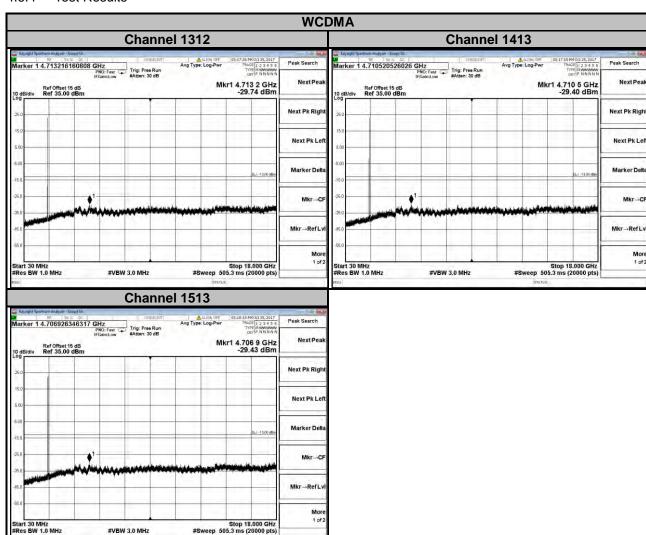


4.6.3 Test Procedure

- a. The EUT makes a phone call to the communication simulator. All measurements were done at low, middle and high operational frequency range.
- b. Measuring frequency range is from 30 MHz to 8 GHz for LTE Band 12/13/17 and from 30 MHz to 18 GHz for WCDMA & LTE Band 4. 10 dB attenuation pad is connected with spectrum. RBW = 1 MHz and VBW = 3 MHz are used for conducted emission measurement.

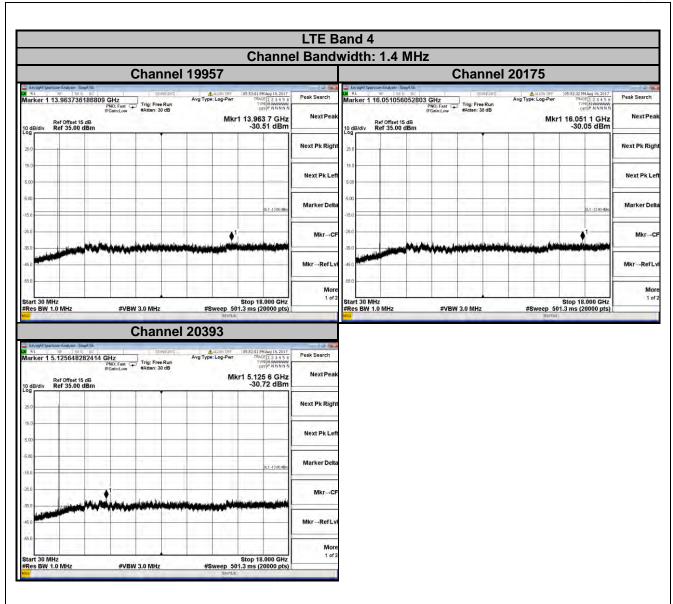


4.6.4 Test Results

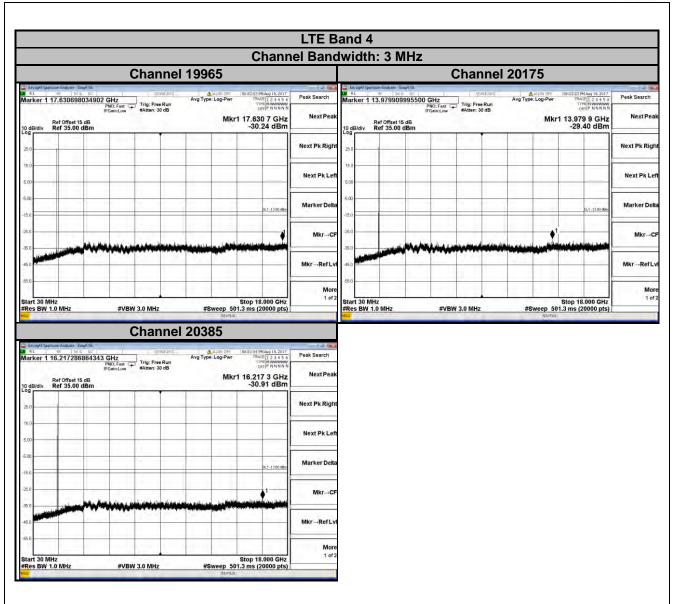


#VBW 3,0 MHz

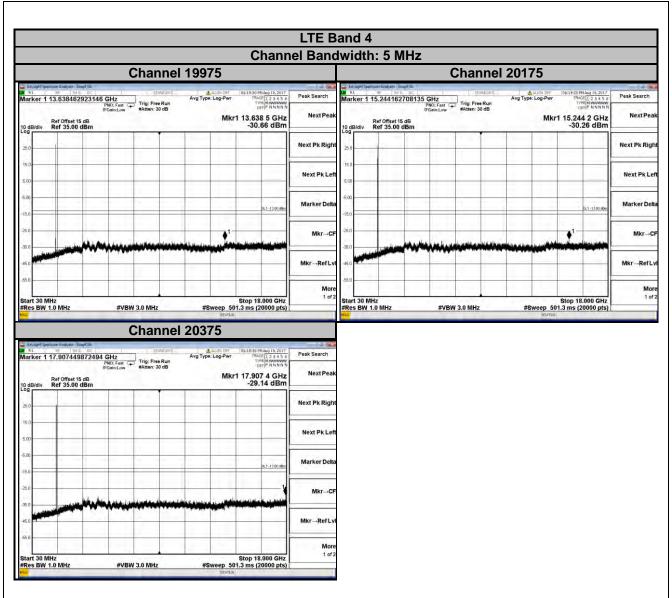




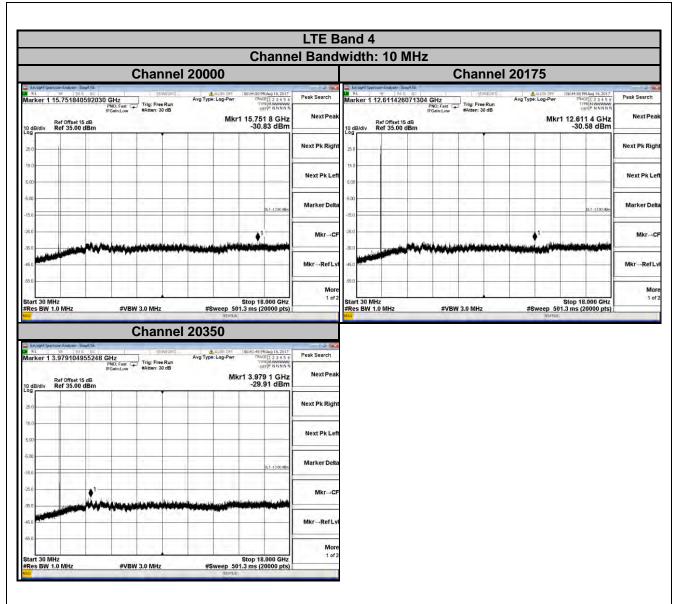




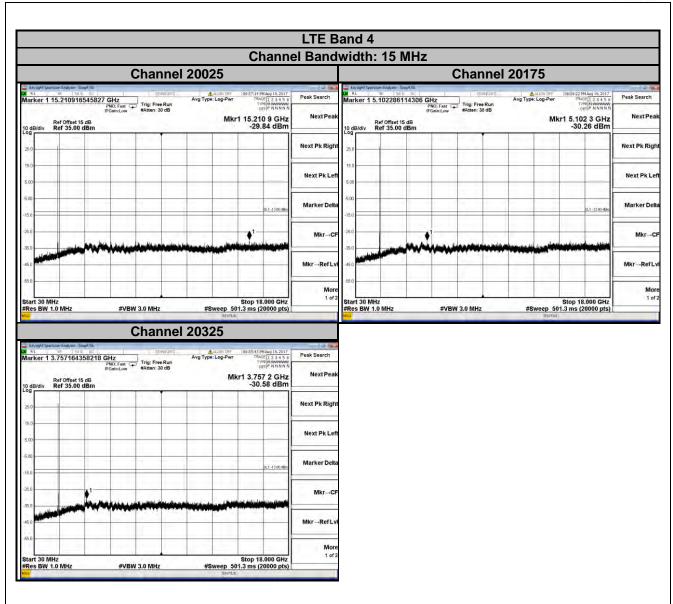




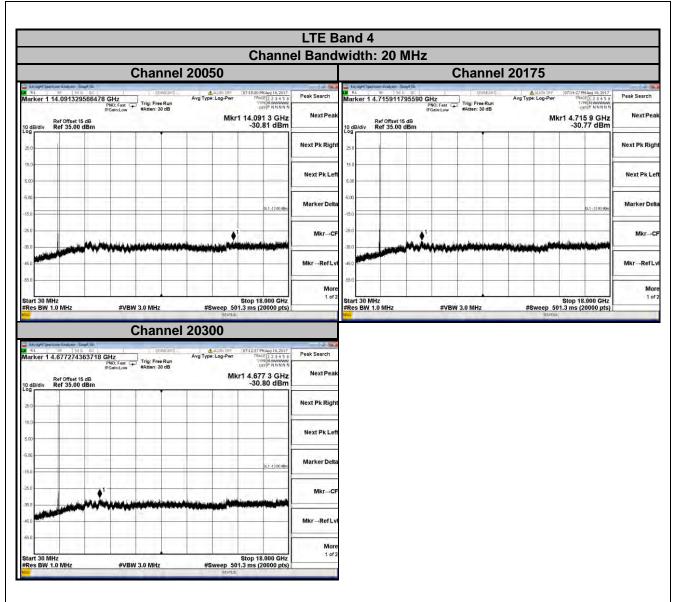




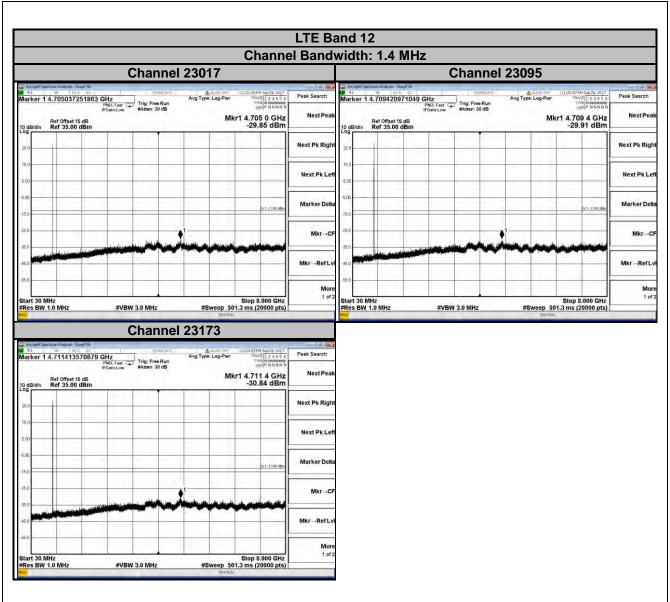




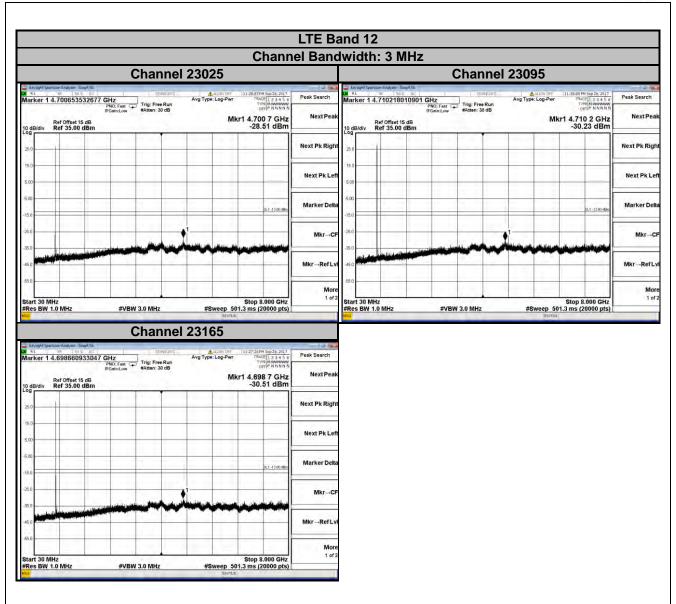




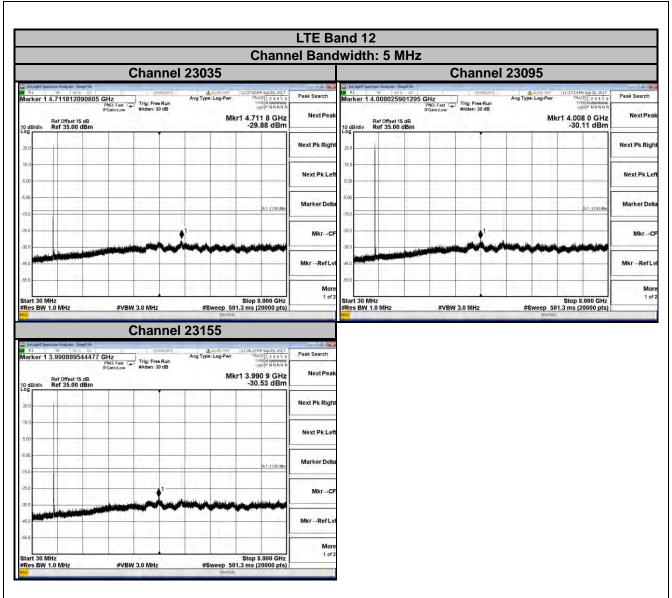




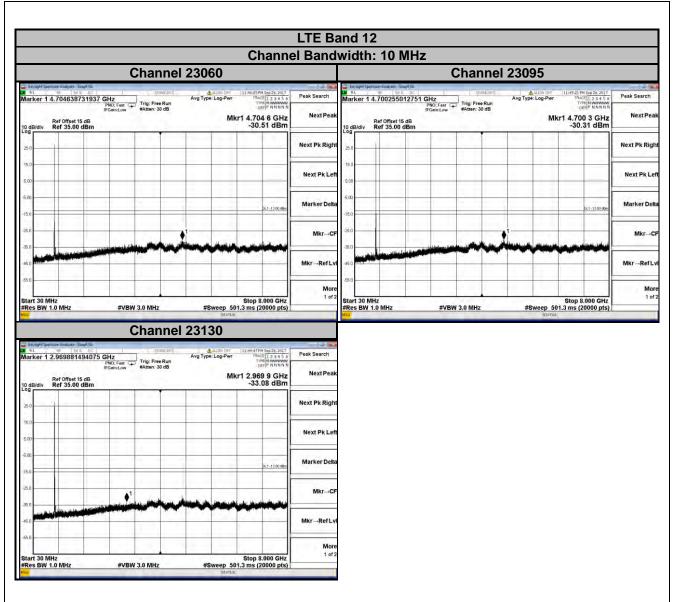




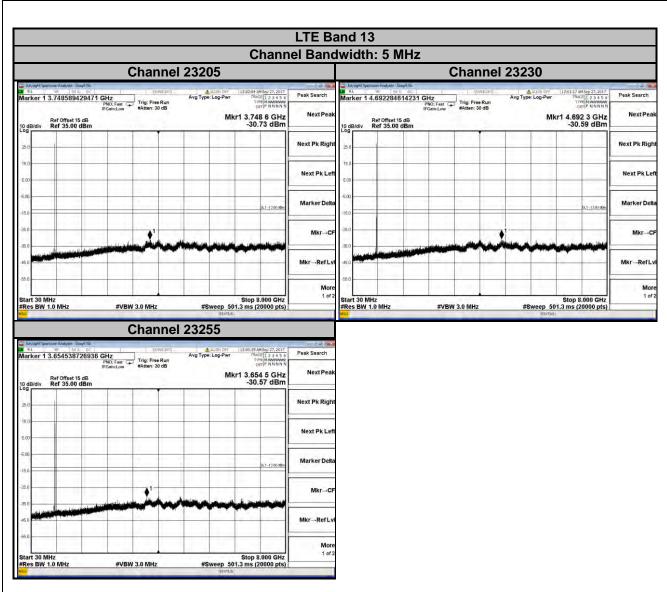


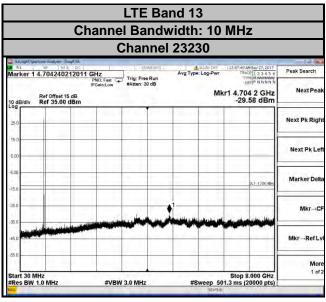




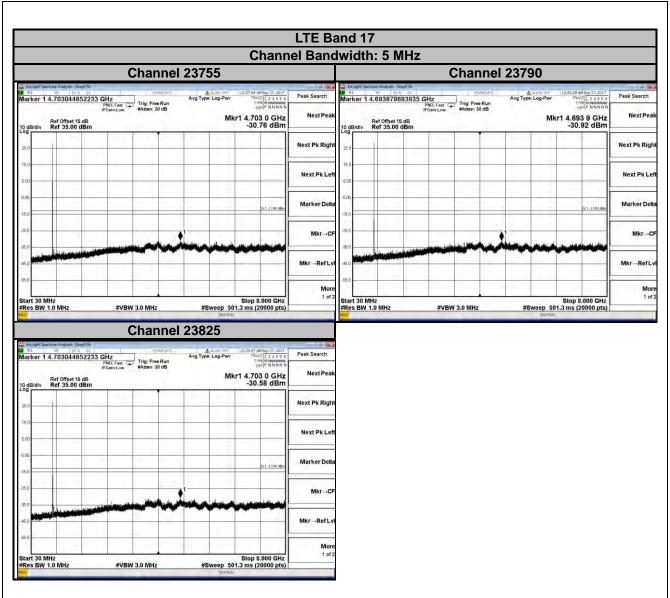




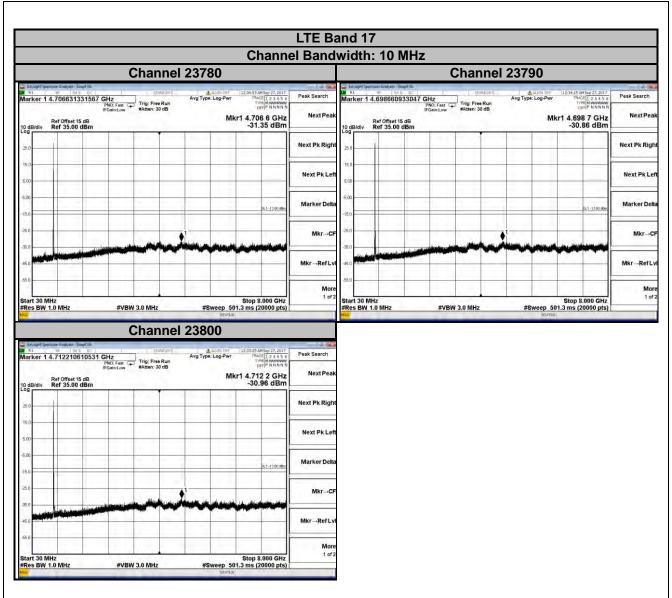














4.7 Radiated Emission Measurement

4.7.1 Limits of Radiated Emission Measurement

- a. The power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) by at least 43 +10 log10(P) dB. The limit of emission is equal to -13 dBm.
- b. For operations in the 775-788 MHz, emissions in the band 1559-1610 MHz shall be limited to -70 dBW/MHz. The limit of emissions is equal to -40 dBm.

4.7.2 Test Procedure

- a. Substitution method is used for E.I.R.P measurement. In the semi-anechoic chamber, EUT placed on the 0.8 m (below or equal 1 GHz) and/or 1.5 m (above 1 GHz) height of Turn Table, rotated the table around 360 degrees to search the maximum radiation power and receiver antenna shall be rotated vertical and horizontal polarization and moved height from 1 m to 4 m to find the maximum polar radiated power. The "Read Value" is the spectrum reading the maximum power value.
- b. The substitution horn antenna is substituted for EUT at the same position and signals generator export the CW signal to the substitution antenna via a TX cable. Rotated the Turn Table and moved receiving antenna to find the maximum radiation power. Adjust output power level of S.G to get a Value of spectrum reading equal to "Read Value" of step a. Record the power level of S.G.
- c. EIRP = Output power level of S.G TX cable loss + Antenna gain of substitution horn.
- d. E.R.P power can be calculated form E.I.R.P power by subtracting the gain of dipole, E.R.P power = E.I.P.R power 2.15 dBi.

Note: The resolution bandwidth of spectrum analyzer is 1 MHz and the video bandwidth is 3 MHz.

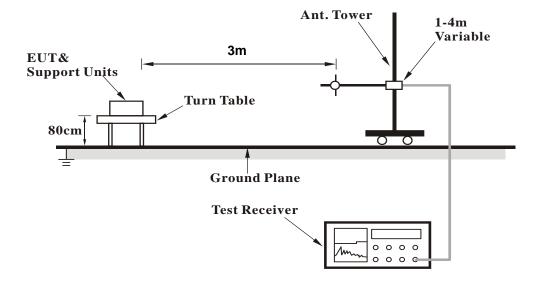
4.7.3 Deviation from Test Standard

No deviation.

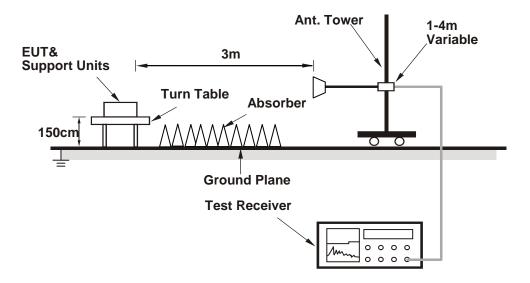


4.7.4 Test Setup

<Radiated Emission below or equal 1 GHz>



<Radiated Emission above 1 GHz>



For the actual test configuration, please refer to the attached file (Test Setup Photo).

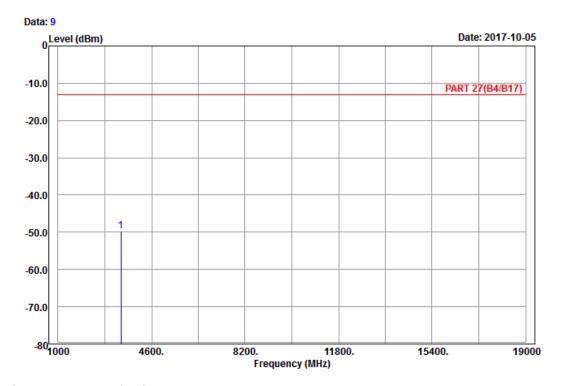


4.7.5 Test Results

WCDMA: Low Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal

Remark : Band IV_Link_CH1312

Tested by: Karl Lee

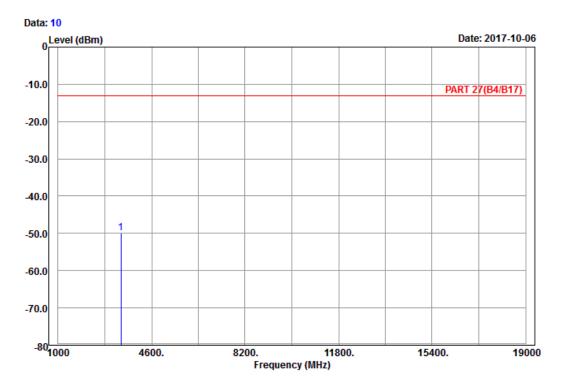
Read Limit Over
Freq Level Level Line Limit Factor Remark

MHz dBm dBm dBm dB dB

1 pp 3424.80 -49.72 -64.09 -13.00 -36.72 14.37 Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : Band IV_Link_CH1312

Tested by: Karl Lee

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dB dB

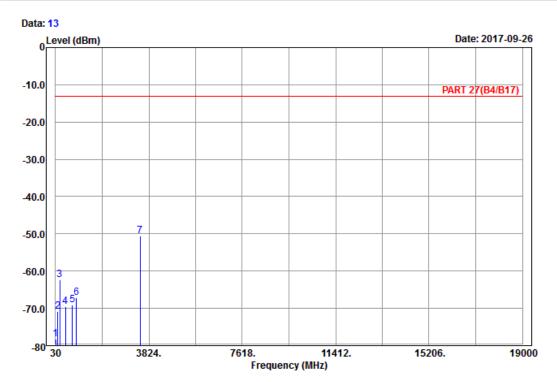
1 pp 3424.80 -50.03 -64.40 -13.00 -37.03 14.37 Peak



Middle Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal

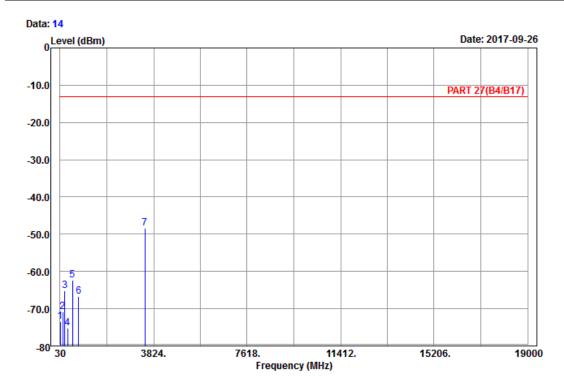
Remark : Band IV_Link_CH1413

Tested by: Charles Hsiao

	,						
			Read	Limit	0ver		
	Freq	Level	Level	Line	Limit	Factor	Remark
	MHz	dBm	dBm	dBm	dB	dB	
1	35.67	-78.22	-67.50	-13.00	-65.22	-10.72	Peak
2	118.29	-70.85	-62.47	-13.00	-57.85	-8.38	Peak
3	202.26	-62.30	-56.16	-13.00	-49.30	-6.14	Peak
4	430.20	-69.46	-66.04	-13.00	-56.46	-3.42	Peak
5	708.10	-69.18	-68.66	-13.00	-56.18	-0.52	Peak
6	885.20	-67.09	-69.56	-13.00	-54.09	2.47	Peak
7 pp	3465.20	-50.57	-64.91	-13.00	-37.57	14.34	Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical

Remark : Band IV_Link_CH1413

Tested by: Charles Hsiao

	Freq	Level		Limit Line		Factor	Remark
	MHz	dBm	dBm	dBm	dB	dB	
1	38.10	-73.48	-63.51	-13.00	-60.48	-9.97	Peak
2	136.38	-70.75	-63.07	-13.00	-57.75	-7.68	Peak
3	221.70	-65.14	-59.26	-13.00	-52.14	-5.88	Peak
4	333.60	-75.17	-69.60	-13.00	-62.17	-5.57	Peak
5	528.90	-62.40	-59.18	-13.00	-49.40	-3.22	Peak
6	778.80	-66.68	-67.29	-13.00	-53.68	0.61	Peak
7 p	p 3465.20	-48.41	-62.75	-13.00	-35.41	14.34	Peak

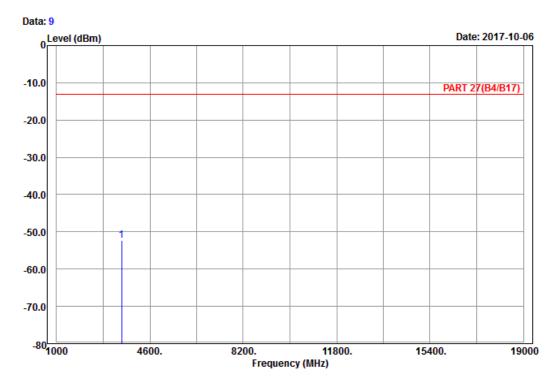


Report Format Version: 6.1.1

High Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal

Remark : Band IV_Link_CH1513

Tested by: Karl Lee

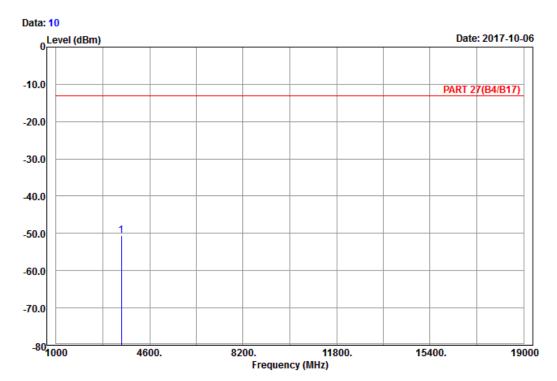
Read Limit Over
Freq Level Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 3505.20 -52.35 -66.63 -13.00 -39.35 14.28 Peak







: 966 chamber 1

Condition: PART 27(B4/B17) Vertical

Remark : Band IV_Link_CH1513

Tested by: Karl Lee

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dBm dB

1 pp 3505.20 -50.49 -64.77 -13.00 -37.49 14.28 Peak



Report Format Version: 6.1.1

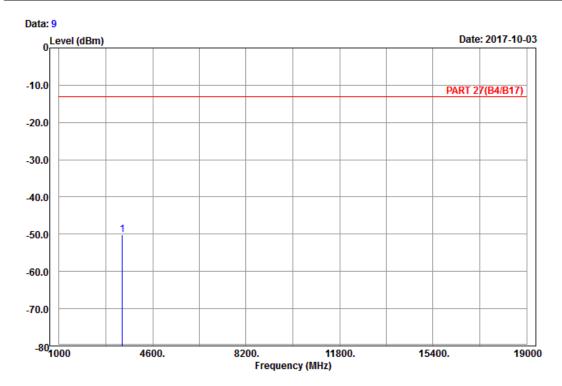
LTE Band 4

Channel Bandwidth: 20 MHz / QPSK

Low Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal Remark : LTE_Band 4_Link_CH20050

Tested by: Charles Hsiao

Read Limit Over

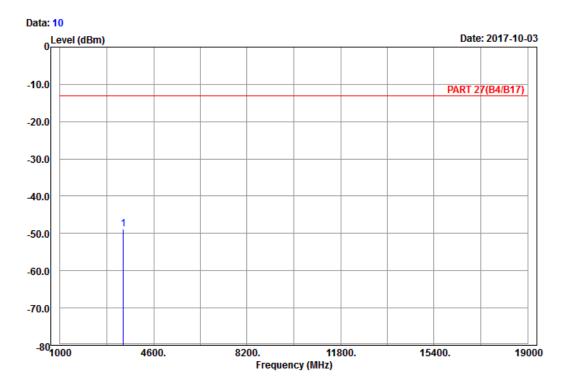
Freq Level Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 3440.00 -50.20 -64.55 -13.00 -37.20 14.35 Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : LTE_Band 4_Link_CH20050

Tested by: Charles Hsiao

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dB dB

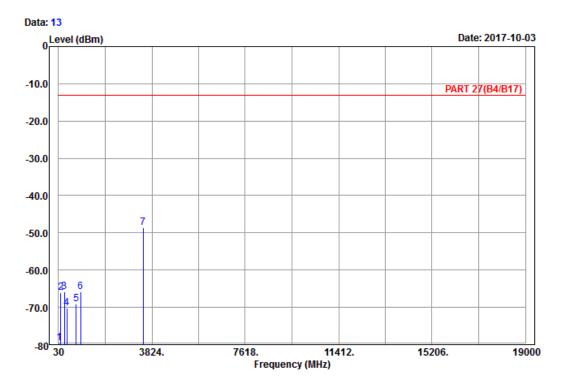
1 pp 3440.00 -48.83 -63.18 -13.00 -35.83 14.35 Peak



Middle Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



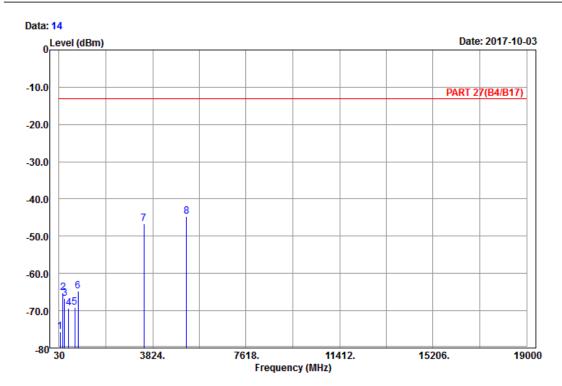
Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal Remark : LTE_Band 4_Link_CH20175

	by. Kui						
			Read	Limit	0ver		
	Freq	Level	Level	Line	Limit	Factor	Remark
_							
	MHz	dBm	dBm	dBm	dB	dB	
1	53.49	-79.62	-65.56	-13.00	-66.62	-14.06	Peak
2	127.47	-66.03	-58.20	-13.00	-53.03	-7.83	Peak
3	263.28	-65.83	-60.21	-13.00	-52.83	-5.62	Peak
4	373.50	-70.14	-66.00	-13.00	-57.14	-4.14	Peak
5	752.20	-69.11	-67.99	-13.00	-56.11	-1.12	Peak
6	925.80	-65.94	-70.00	-13.00	-52.94	4.06	Peak
7 pp	3465.00	-48.57	-62.91	-13.00	-35.57	14.34	Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : LTE_Band 4_Link_CH20175

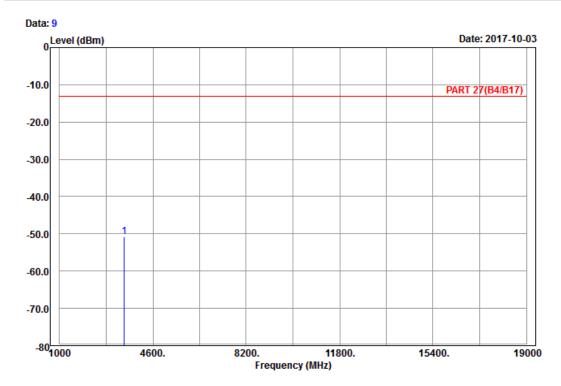
			Kead	Limit	Over		
	Freq	Level	Level	Line	Limit	Factor	Remark
-	MHz	dBm	dBm	dBm	dB	dB	
1	64.83	-75.67	-62.29	-13.00	-62.67	-13.38	Peak
2	193.35	-65.12	-59.25	-13.00	-52.12	-5.87	Peak
3	254.64	-66.63	-61.08	-13.00	-53.63	-5.55	Peak
4	416.90	-69.27	-66.15	-13.00	-56.27	-3.12	Peak
5	659.80	-69.02	-68.84	-13.00	-56.02	-0.18	Peak
6	804.70	-64.74	-66.70	-13.00	-51.74	1.96	Peak
7	3465.00	-46.69	-61.03	-13.00	-33.69	14.34	Peak
8 pp	5197.50	-44.74	-64.86	-13.00	-31.74	20.12	Peak



High Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal Remark : LTE_Band 4_Link_CH20300

Tested by: Karl Lee

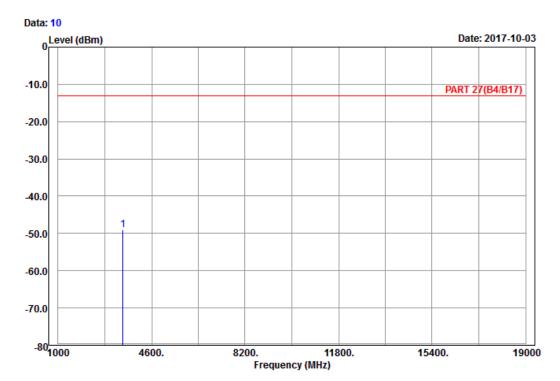
Read Limit Over Freq Level Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 3490.00 -50.87 -65.18 -13.00 -37.87 14.31 Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : LTE_Band 4_Link_CH20300

Tested by: Karl Lee

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dBm dB dB

1 pp 3490.00 -49.02 -63.33 -13.00 -36.02 14.31 Peak



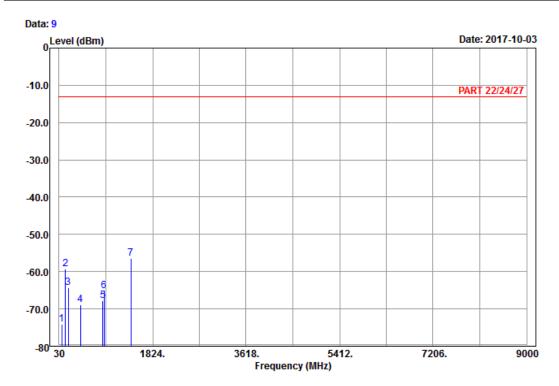
LTE Band 12

Channel Bandwidth: 10 MHz / QPSK

Low Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



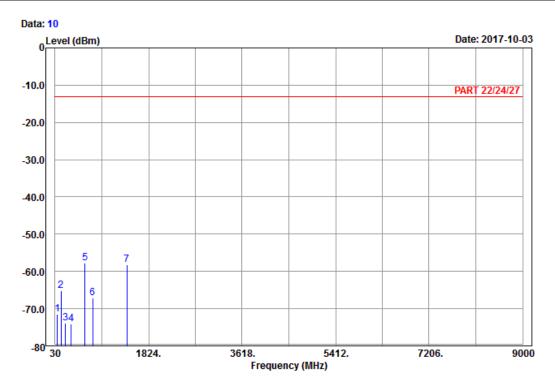
Site : 966 chamber 1

Condition: PART 22/24/27 Horizontal Remark : LTE_Band 12_Link_CH23060

			Read	Limit	0ver		
	Freq	Level	Level	Line	Limit	Factor	Remark
_							
	MHz	dBm	dBm	dBm	dB	dB	
1	82.11	-74.10	-62.55	-13.00	-61.10	-11.55	Peak
2	149.34	-59.32	-51.39	-13.00	-46.32	-7.93	Peak
3	207.12	-64.25	-58.17	-13.00	-51.25	-6.08	Peak
4	436.50	-68.80	-65.25	-13.00	-55.80	-3.55	Peak
5	869.80	-67.77	-69.80	-13.00	-54.77	2.03	Peak
6	894.30	-65.18	-67.90	-13.00	-52.18	2.72	Peak
7 pp	1408.00	-56.48	-62.84	-13.00	-43.48	6.36	Peak







Site : 966 chamber 1

Condition: PART 22/24/27 Vertical Remark : LTE_Band 12_Link_CH23060

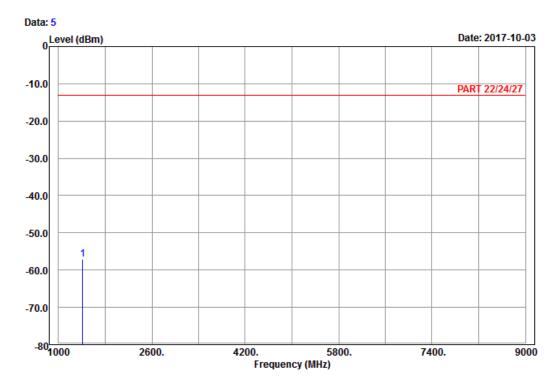
	. Dy. Kai	1 222					
			Read	Limit	0ver		
	Freq	Level	Level	Line	Limit	Factor	Remark
_							
	MHz	dBm	dBm	dBm	dB	dB	
1	71.58	-71.59	-59.07	-13.00	-58.59	-12.52	Peak
2	145.29	-65.24	-57.41	-13.00	-52.24	-7.83	Peak
3	228.45	-73.83	-68.04	-13.00	-60.83	-5.79	Peak
4	342.00	-74.20	-68.73	-13.00	-61.20	-5.47	Peak
5 pp	599.60	-57.81	-58.20	-13.00	-44.81	0.39	Peak
6	749.40	-67.12	-65.81	-13.00	-54.12	-1.31	Peak
7	1408.00	-58.18	-64.54	-13.00	-45.18	6.36	Peak



Middle Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 22/24/27 Horizontal Remark : LTE_Band 12_Link_CH23095

Tested by: Karl Lee

Read Limit Over

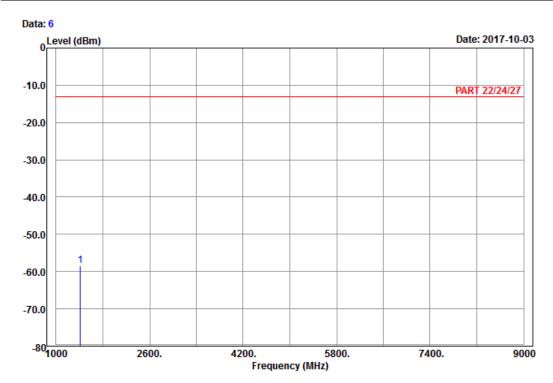
Freq Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 1415.00 -57.04 -63.40 -13.00 -44.04 6.36 Peak







Site : 966 chamber 1

Condition: PART 22/24/27 Vertical Remark : LTE_Band 12_Link_CH23095

Tested by: Karl Lee

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dBm dB dB

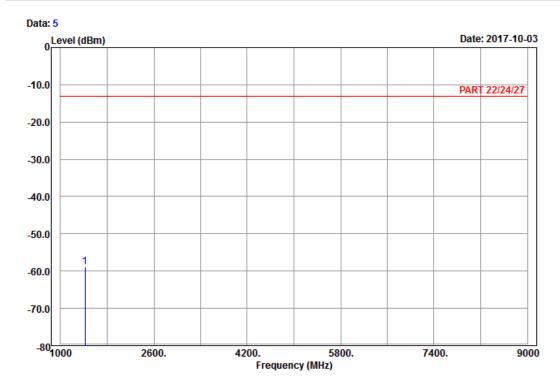
1 pp 1415.00 -58.38 -64.74 -13.00 -45.38 6.36 Peak



High Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 22/24/27 Horizontal Remark : LTE_Band 12_Link_CH23130

Tested by: Karl Lee

Read Limit Over

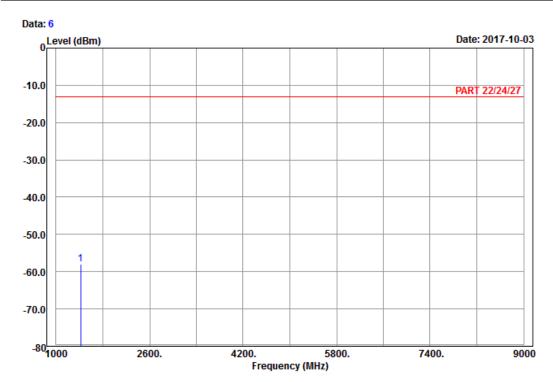
Freq Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 1422.00 -58.76 -65.12 -13.00 -45.76 6.36 Peak







Site : 966 chamber 1

Condition: PART 22/24/27 Vertical Remark : LTE_Band 12_Link_CH23130

Tested by: Karl Lee

Read Limit Over

Freq Level Level Line Limit Factor Remark

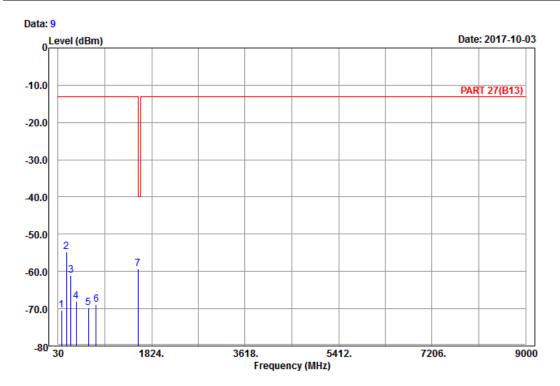
MHz dBm dBm dBm dB dB dB

1 pp 1422.00 -57.97 -64.33 -13.00 -44.97 6.36 Peak



LTE Band 13 Channel Bandwidth: 10 MHz / QPSK





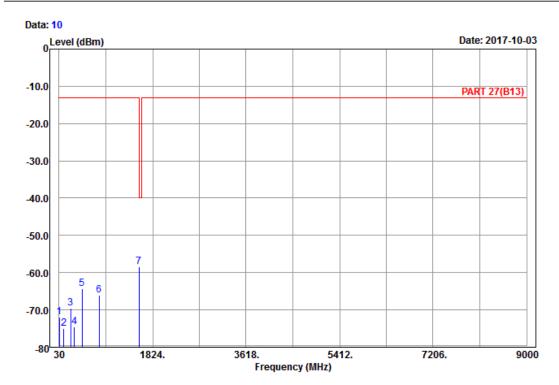
Site : 966 chamber 1

Condition: PART 27(B13) Horizontal Remark : LTE_Band 13_Link_CH23230

	-,						
			Read	Limit	0ver		
	Freq	Level	Level	Line	Limit	Factor	Remark
_							
	MHz	dBm	dBm	dBm	dB	dB	
1	98.58	-70.42	-60.24	-13.00	-57.42	-10.18	Peak
2	190.65	-54.63	-48.85	-13.00	-41.63	-5.78	Peak
3	275.16	-60.94	-55.20	-13.00	-47.94	-5.74	Peak
4	374.90	-68.02	-63.99	-13.00	-55.02	-4.03	Peak
5	614.30	-69.71	-69.98	-13.00	-56.71	0.27	Peak
6	756.40	-68.80	-67.94	-13.00	-55.80	-0.86	Peak
7 pp	1564.00	-59.32	-66.18	-40.00	-19.32	6.86	Peak







Site : 966 chamber 1

Condition: PART 27(B13) Vertical Remark : LTE_Band 13_Link_CH23230

	Freq	Level		Limit Line		Factor	Remark
_	MHz	dBm	dBm	dBm	dB	dB	
1	35.67	-71.99	-61.27	-13.00	-58.99	-10.72	Peak
2	122.34	-74.95	-66.82	-13.00	-61.95	-8.13	Peak
3	252.75	-69.59	-64.06	-13.00	-56.59	-5.53	Peak
4	321.70	-74.61	-68.91	-13.00	-61.61	-5.70	Peak
5	473.60	-64.25	-59.74	-13.00	-51.25	-4.51	Peak
6	796.30	-65.99	-67.75	-13.00	-52.99	1.76	Peak
7 pp	1564.00	-58.50	-65.36	-40.00	-18.50	6.86	Peak



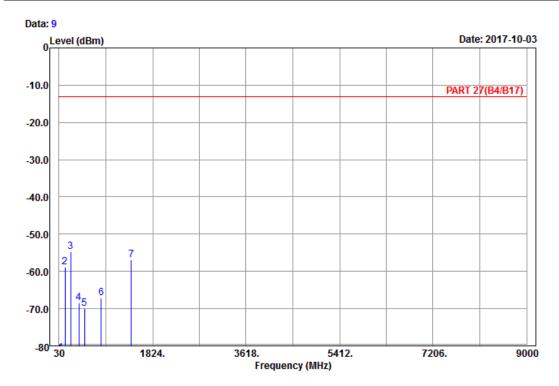
LTE Band 17

Channel Bandwidth: 10 MHz / QPSK

Low Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

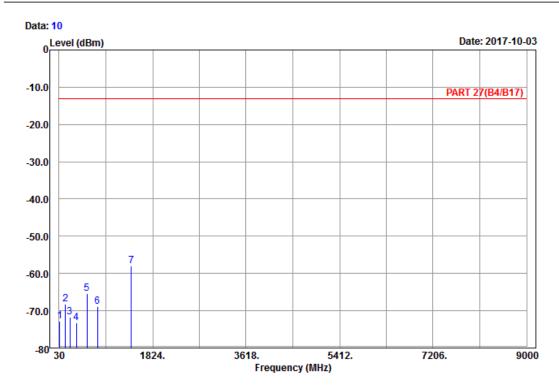
Condition: PART 27(B4/B17) Horizontal Remark : LTE_Band 17_Link_CH23780

Tested by: Charles Hsiao

	Freq	Level		Limit Line		Factor	Remark
_	MHz	dBm	dBm	dBm	dB	dB	
1	63.48	-82.01	-68.50	-13.00	-69.01	-13.51	Peak
2	139.35	-58.94	-51.25	-13.00	-45.94	-7.69	Peak
3 рр	249.78	-54.69	-49.18	-13.00	-41.69	-5.51	Peak
4	409.20	-68.43	-65.48	-13.00	-55.43	-2.95	Peak
5	517.70	-70.02	-66.02	-13.00	-57.02	-4.00	Peak
6	840.40	-67.14	-68.70	-13.00	-54.14	1.56	Peak
7	1418.00	-56.86	-63.22	-13.00	-43.86	6.36	Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : LTE_Band 17_Link_CH23780

Tested by: Charles Hsiao

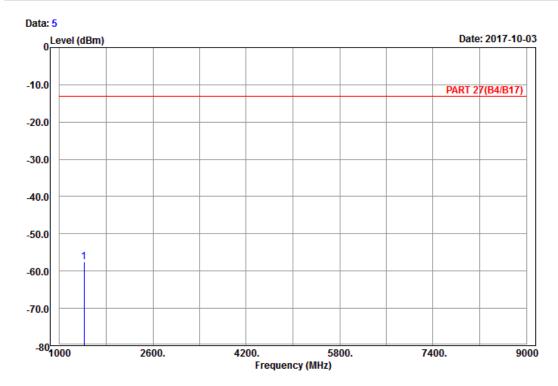
			Read	Limit	0ver		
	Freq	Level	Level	Line	Limit	Factor	Remark
_							
	MHz	dBm	dBm	dBm	dB	dB	
1	39.72	-72.81	-63.60	-13.00	-59.81	-9.21	Peak
2	150.96	-68.18	-60.26	-13.00	-55.18	-7.92	Peak
3	233.04	-71.75	-66.01	-13.00	-58.75	-5.74	Peak
4	365.10	-73.28	-68.68	-13.00	-60.28	-4.60	Peak
5	567.40	-65.34	-64.40	-13.00	-52.34	-0.94	Peak
6	766.20	-68.87	-68.65	-13.00	-55.87	-0.22	Peak
7 pp	1418.00	-57.89	-64.25	-13.00	-44.89	6.36	Peak



Middle Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal Remark : LTE_Band 17_Link_CH23790

Tested by: Charles Hsiao

Read Limit Over

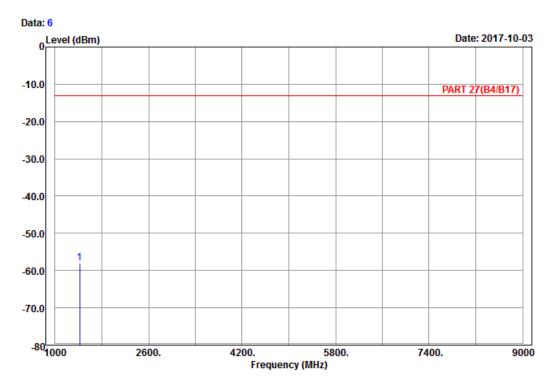
Freq Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 1420.00 -57.51 -63.87 -13.00 -44.51 6.36 Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : LTE_Band 17_Link_CH23790

Tested by: Charles Hsiao

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dBm dB dB

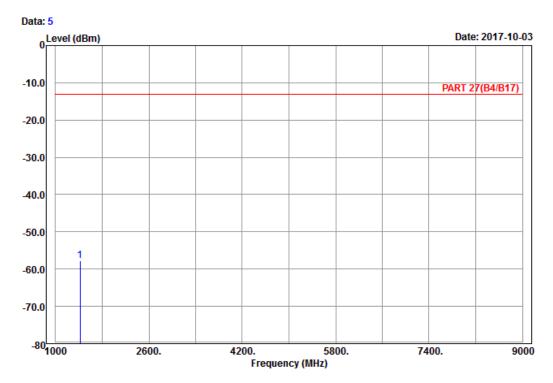
1 pp 1420.00 -57.94 -64.30 -13.00 -44.94 6.36 Peak



High Channel



Bureau Veritas Consumer Products Services Ltd., Taoyuan Branch



Site : 966 chamber 1

Condition: PART 27(B4/B17) Horizontal Remark : LTE_Band 17_Link_CH23800

Tested by: Charles Hsiao

Read Limit Over

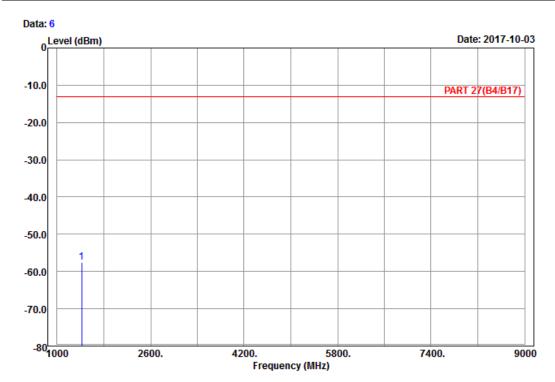
Freq Level Line Limit Factor Remark

MHz dBm dBm dB dB

1 pp 1422.00 -57.84 -64.20 -13.00 -44.84 6.36 Peak







Site : 966 chamber 1

Condition: PART 27(B4/B17) Vertical Remark : LTE_Band 17_Link_CH23800

Tested by: Charles Hsiao

Read Limit Over

Freq Level Level Line Limit Factor Remark

MHz dBm dBm dBm dB dB dB

1 pp 1422.00 -57.46 -63.82 -13.00 -44.46 6.36 Peak



5	Pictures of Test Arrangements
	ase refer to the attached file (Test Setup Photo).



Appendix - Information on the Testing Laboratories

We, Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch, were founded in 1988 to provide our best service in EMC, Radio, Telecom and Safety consultation. Our laboratories are FCC recognized accredited test firms and accredited according to ISO/IEC 17025.

Hsin Chu EMC/RF/Telecom Lab

If you have any comments, please feel free to contact us at the following:

Linko EMC/RF Lab

Tel: 886-2-26052180 Tel: 886-3-6668565 Fax: 886-2-26051924 Fax: 886-3-6668323

Hwa Ya EMC/RF/Safety

Tel: 886-3-3183232 Fax: 886-3-3270892

Email: service.adt@tw.bureauveritas.com
Web Site: www.bureauveritas-adt.com

The address and road map of all our labs can be found in our web site also.

--- END ---